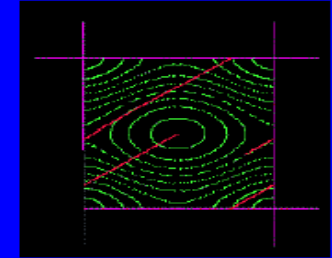
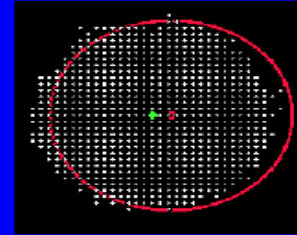
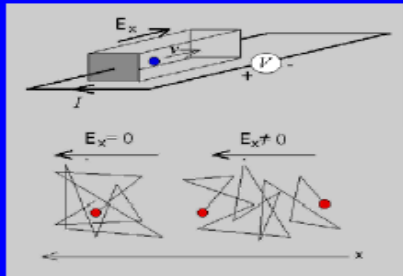


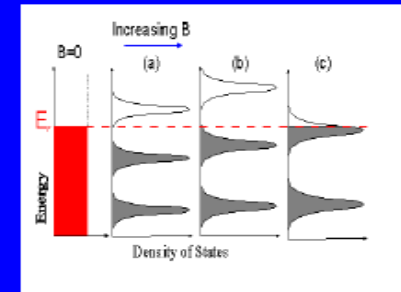
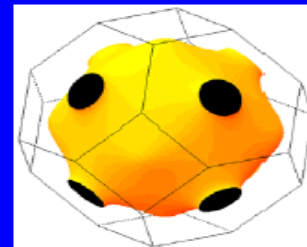
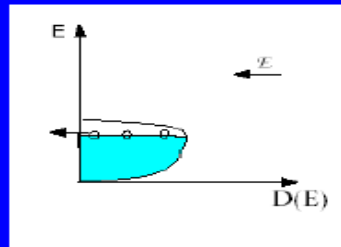
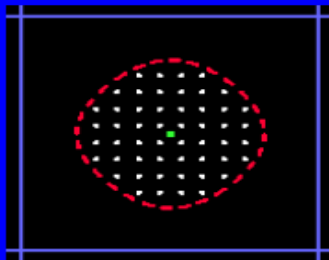
Transport Phenomena in Solids

Motions of electrons and transport phenomena



$$\sigma = \frac{ne^2\tau}{m}$$

$$\left(\frac{1}{m^*}\right)_{ij} = \frac{1}{\hbar^2} \sum_j \frac{\partial^2 E(\vec{k})}{\partial k_i \partial k_j}$$



TUNNEL MAGNETORESISTANCE

Recap

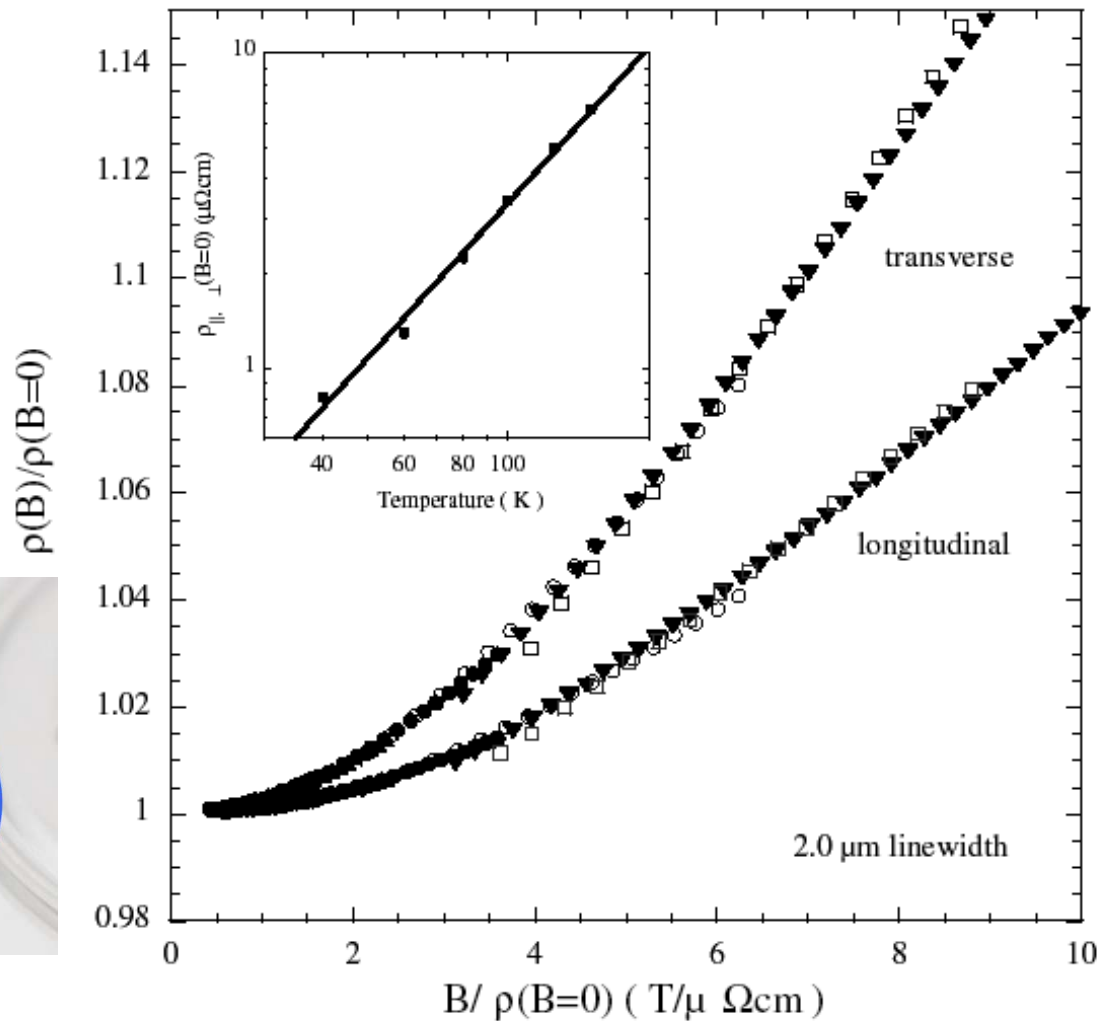
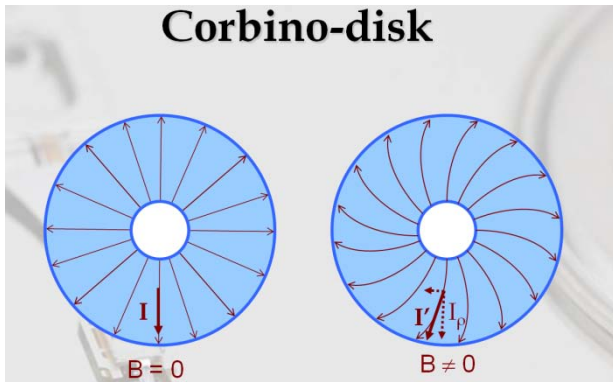
Magnetoresistance is the property of a material to change the value of its **electrical resistance** when an **external magnetic field** is applied to it.

$$MR = (\rho(H) - \rho(0)) / \rho(0)$$

The level of magnetoresistance shown by a material is usually expressed in terms of the **percentage change in resistance** from the highest to the lowest resistance and is usually of the order of **a few percent**. The main application for MR sensors is in the read heads of hard disk drives.

Ordinary Magnetoresistance

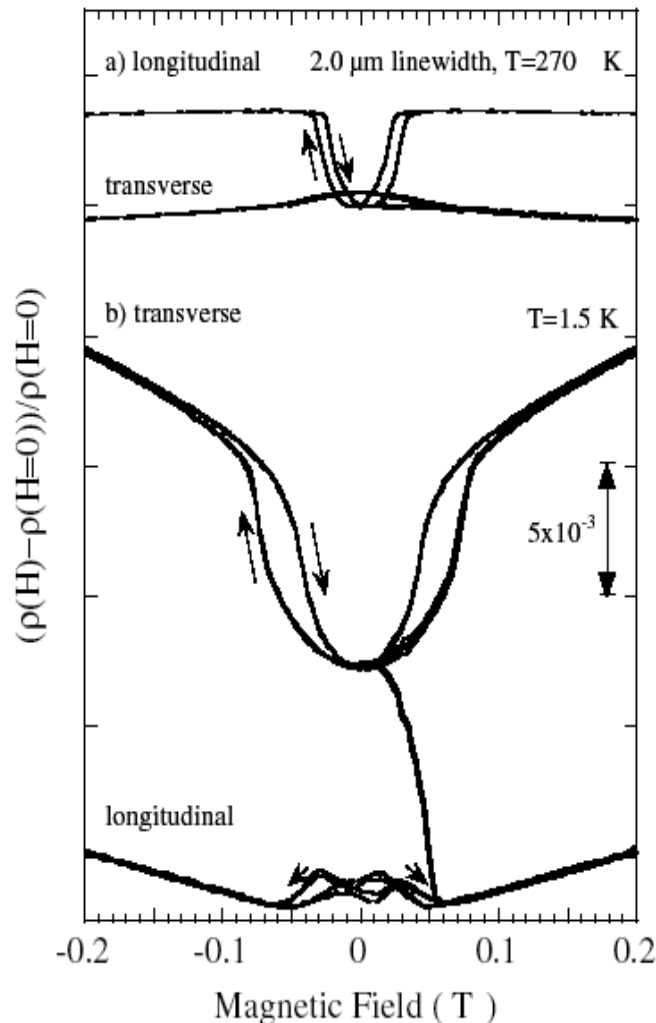
Lorentz force acting on trajectory of electron; longitudinal magnetoresistance (MR).



A.D. Kent *et al*
J. Phys. Cond.
Mat. **13**, R461
(2001)

Figure 10. Scaling plot of transverse and longitudinal MR above magnetic saturation for a 2 μm wire in the form $\rho(B)/\rho(B = 0)$ versus $B/\rho(B = 0)$ at temperatures of (open squares) 1.5 K, (open triangles down) 40 K, (open circles) 60 K, (solid circles) 80 K, (solid triangles up) 100 K, (solid diamonds) 125 K, and (open diamonds) 150 K. The inset shows the scaling parameters $\rho_{||}(B = 0)$ and $\rho_{\perp}(B = 0)$ as a function of temperature on a log-log plot, and overlap on the scale shown in the plot.

Anisotropic MR



a dependence of electrical resistance on the angle between the direction of electric current and orientation of magnetic field

Spin-orbit coupling leads to spin dependent scattering of conduction electrons

Figure 9. (a) MR data at 270 K of a 2 μm wire in the transverse and longitudinal field geometries ($\rho_{\perp}(H = 0, 270 \text{ K}) = 14.7 \mu\Omega\text{cm}$). (b) MR at 1.5 K again in the transverse and longitudinal field geometries ($\rho_{\perp}(H = 0, 1.5 \text{ K}) = 0.74 \mu\Omega\text{cm}$).

A.D. Kent *et al*
J. Phys. Cond.
Mat. **13**, R461
(2001)

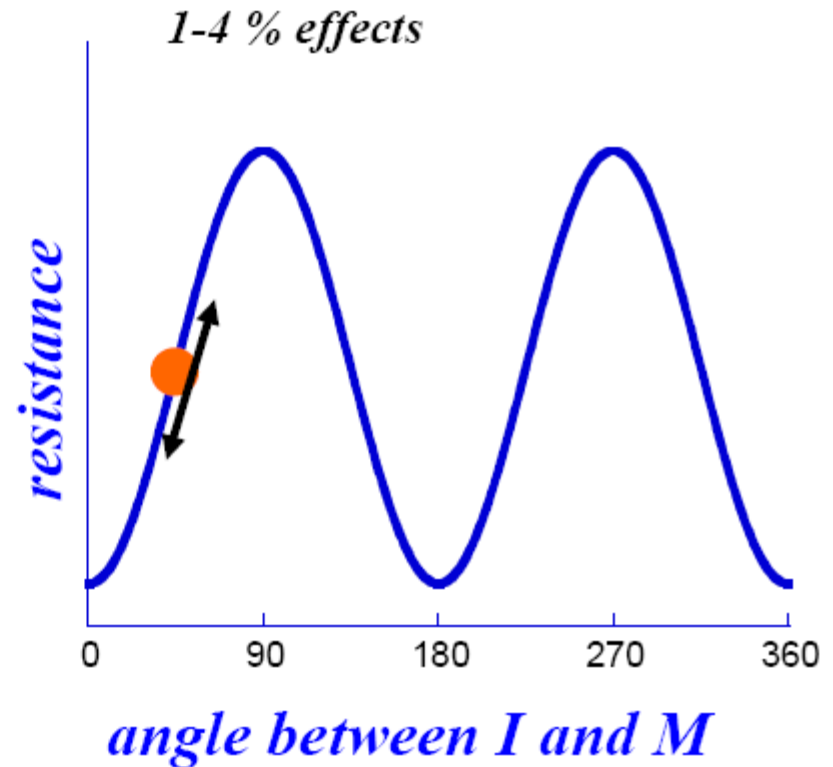
Anisotropic Magneto-resistance (AMR)



high resistance

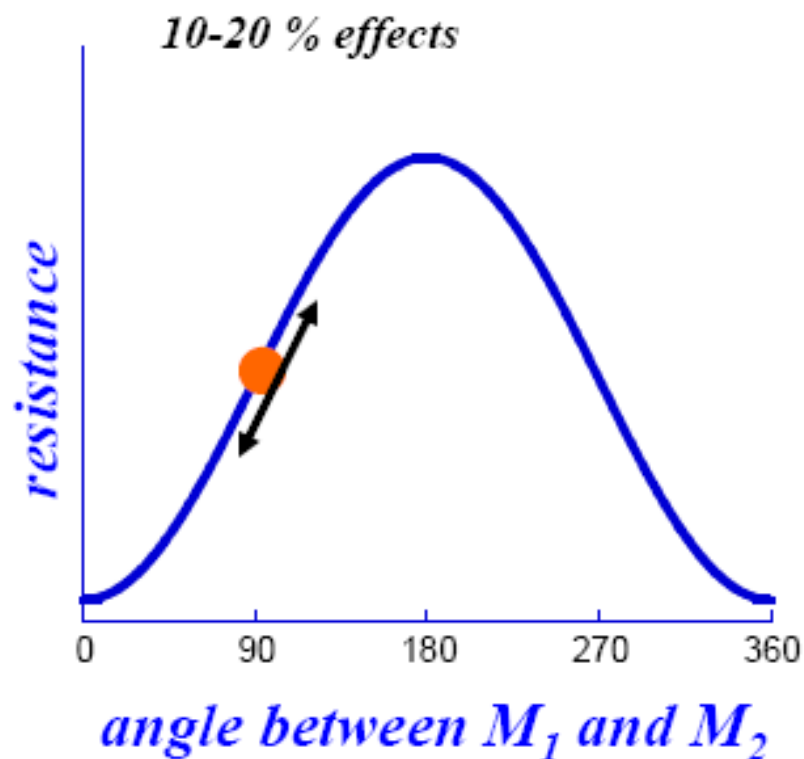
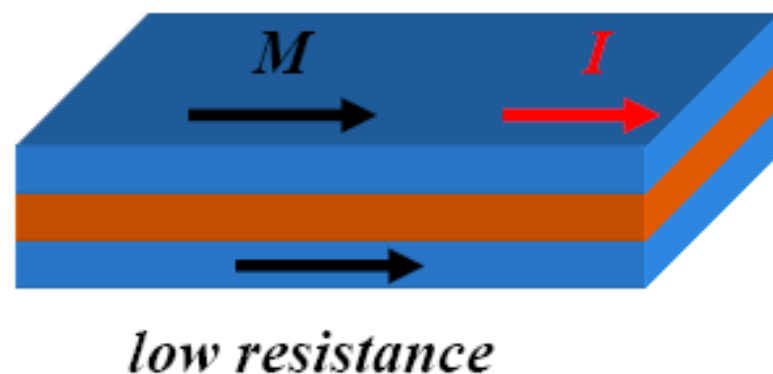
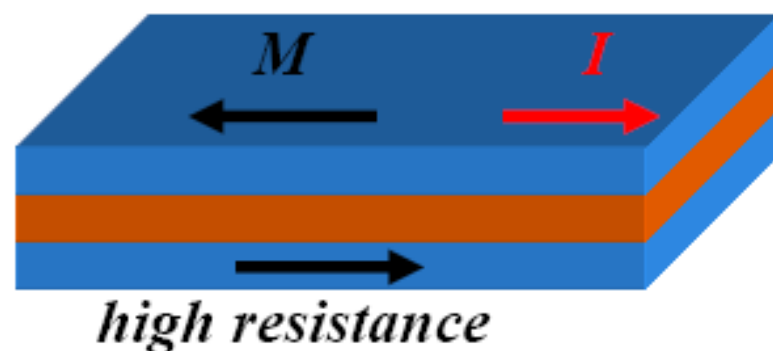


low resistance



Bulk property of magnetic materials

Giant Magneto-resistance (GMR)

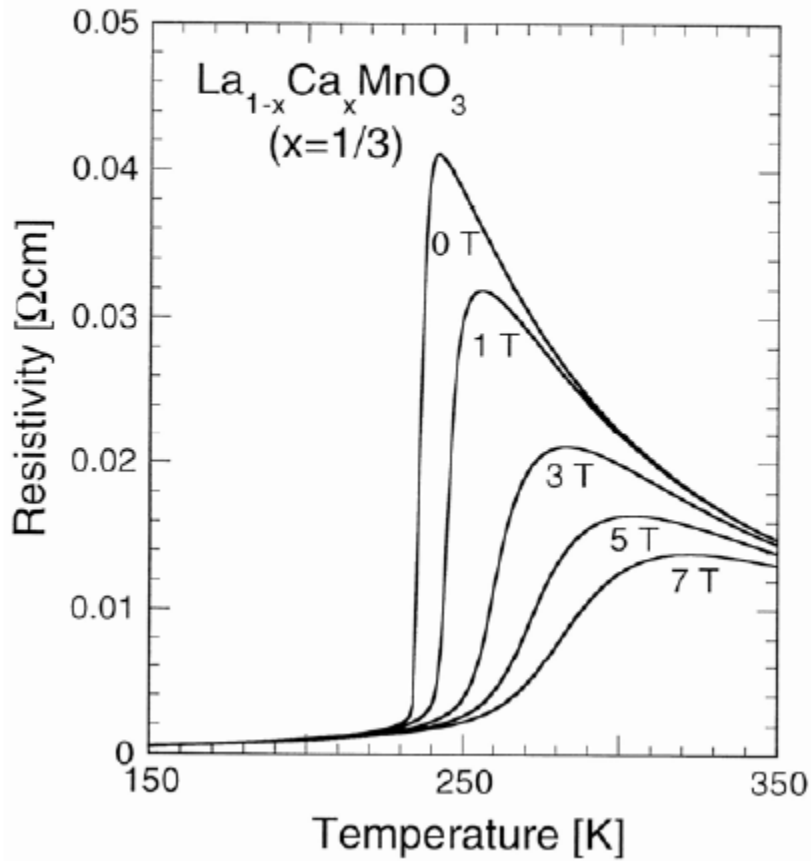


Interface property of magnetic materials

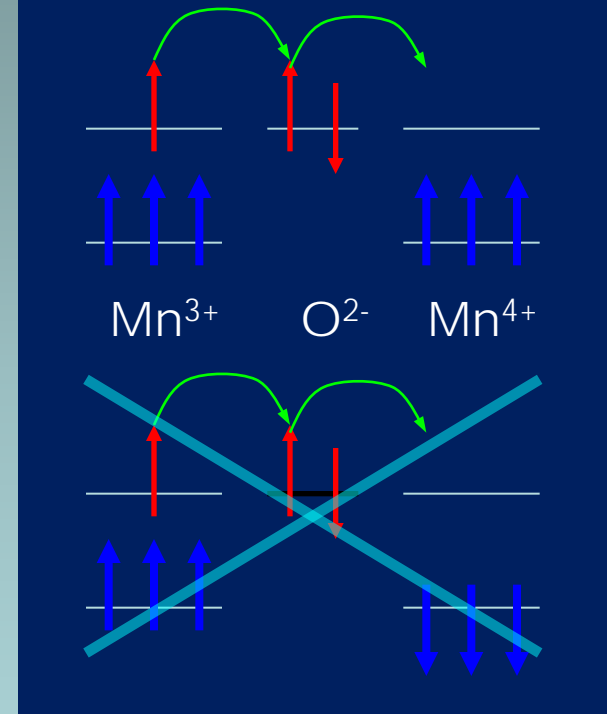
Baibich et al. Phys. Rev. Lett. 61 2472 (1988)

Binasch et al. Phys. Rev. B 39, 4828 (1989); P. Grunberg, U.S. patent # 4,949,039

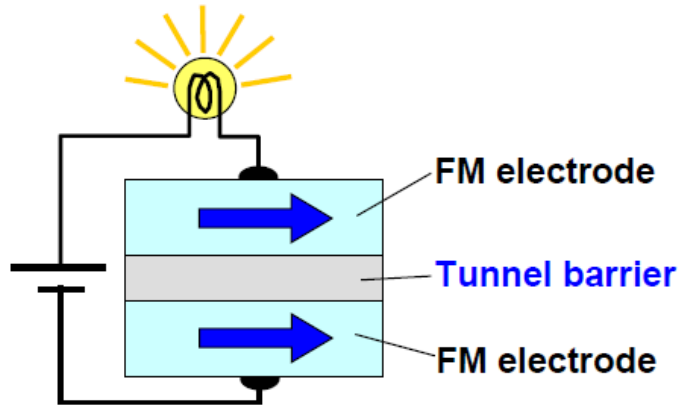
Colossal magnetoresistance (CMR)



Double exchange

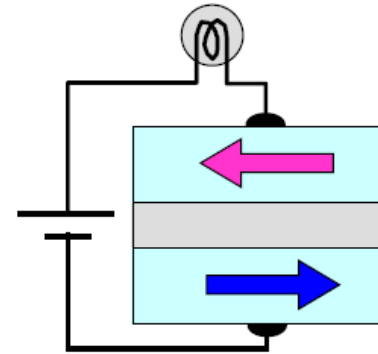


Tunnel magnetoresistance (TMR) effect



Parallel (P) state

Tunnel Resistance R_P : low



Antiparallel (AP) state

Tunnel Resistance R_{AP} : high

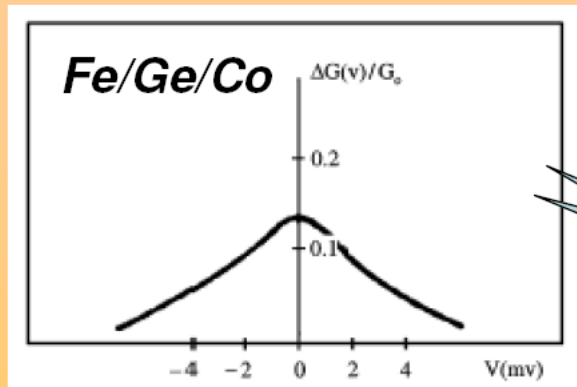
Magnetic tunnel junction (MTJ)

MR ratio $\equiv (R_{AP} - R_P) / R_P$ (performance index)

S. Yuasa et al.

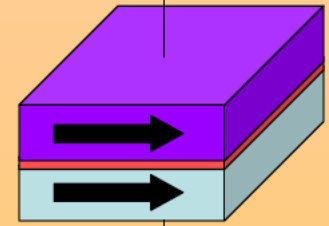
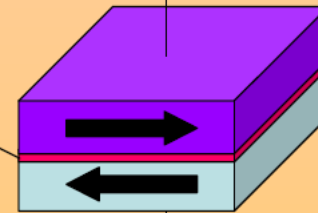
http://www.jst.go.jp/sicp/ws2009_sp1st/presentation/15.pdf

TUNNEL MAGNETORESISTANCE (TMR): how it all started



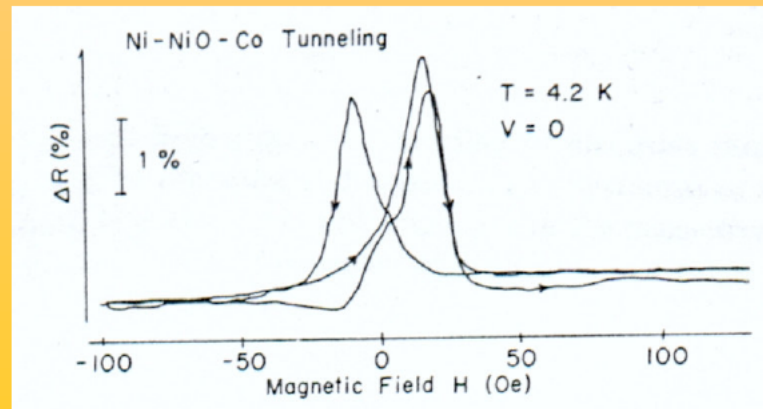
1975

insulator



1982

Julliere, *Phys. Lett.* 54A (1975) 225



Maekawa and Gaefvert, *IEEE Transactions on Magnetics* 18 (1982) 707

1995

CoFe/Al₂O₃/Co

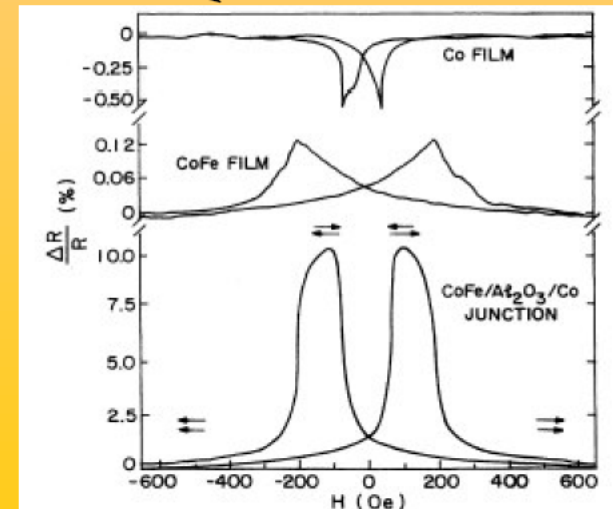


FIG. 2. Resistance of CoFe/Al₂O₃/Co junction plotted as a function of H in the film plane, at 295 K. Also shown is the variation in the CoFe and Co film resistance. The arrows indicate the direction of M in the two films (see text).

J.M. de Teresa,
Universidad de
Zaragoza,
Spain, ESM
2005 Constanta

Moodera et al., *Phys. Rev. Lett.* 74 (1995) 3273

Tunneling magnetoresistance (TMR) is a dramatic change of the tunneling current in magnetic tunnel junctions when relative magnetizations of the two ferromagnetic layers change their alignment.

TMR is a consequence of spin-dependent tunneling.

See:

M. Coldea, Magnetorezistenta, efecte si aplicatii

J.M deTeresa, [New magnetic materials and their functions](#),
2007, Cluj-Napoca, Romania. Summer School

L. Ranno, Spin dependent tunnel transport and spin
polarization, 2003, Brasov.Romania. Summer School

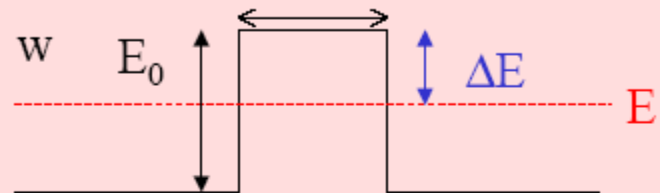
<http://esm.neel.cnrs.fr>

Introduction to Tunnel Effect

L. Ranno, Spin tunnel course, Brasov, 2003, Lab. Louis Néel Grenoble

<http://magnetism.eu/esm/2003-brasov/slides/ranno-slides-1.pdf>

Tunnel Effect has a Quantum Mechanics Origin



A classical electron with energy $E < E_0$ cannot enter the barrier zone
However a quantum electron obeys the Schrödinger equation !

(1D model)

$$-\frac{\hbar^2}{2m} \frac{d^2}{dx^2} |\psi\rangle + V(x) |\psi\rangle = E |\psi\rangle$$

Off the barrier

$$-\frac{\hbar^2}{2m} \frac{d^2}{dx^2} |\psi\rangle = E |\psi\rangle$$

Plane waves

$$|\psi\rangle = e^{i(kr - \omega t)} \quad \text{and} \quad k = \pm \sqrt{\frac{2mE}{\hbar^2}}$$

In the barrier

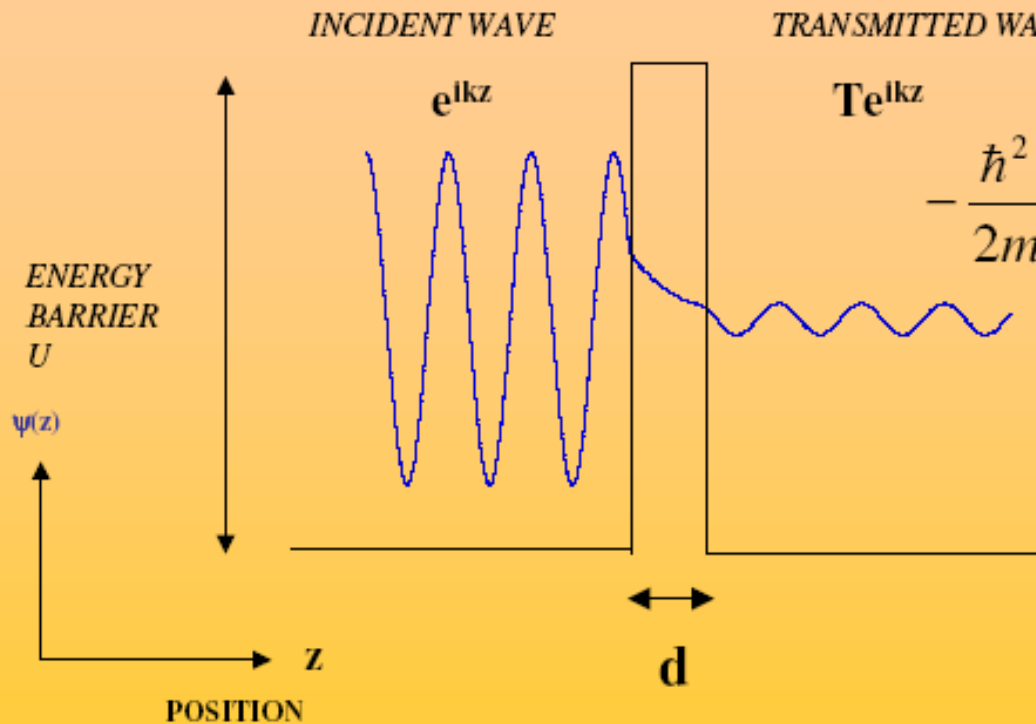
$$-\frac{\hbar^2}{2m} \frac{d^2}{dx^2} |\psi\rangle = (E - E_0) |\psi\rangle \quad \text{and} \quad E - E_0 < 0$$

Evanescent waves

$$|\psi\rangle_b = e^{qr - i\omega t} \quad \text{and} \quad q = \pm \sqrt{\frac{2m\Delta E}{\hbar^2}}$$

TMR: first approach to the tunnel conductance

J.M. de Teresa,
Universidad de Zaragoza,
Spain, ESM 2005 Constanta



$$-\frac{\hbar^2}{2m} \frac{\partial^2 \psi(z)}{\partial z^2} + U\psi(z) = i\hbar \frac{\partial \psi(z)}{\partial t}$$

$$|T_k|^2 = \frac{16k^2 k'^2}{(k^2 + k'^2)^2} e^{-2k'd}$$

$$k' = \sqrt{\frac{2m(U - E_z)}{\hbar^2}}$$

TUNNEL CURRENT:

$$J_k = \frac{i\hbar}{2m} \left(\psi \frac{\partial \psi^*}{\partial z} - \psi^* \frac{\partial \psi}{\partial z} \right)$$

$$J_k \propto |T_k|^2 \propto e^{-2k'd}$$

EXPONENTIAL DEPENDENCE OF THE CURRENT WITH THE BARRIER WIDTH AND THE SQUARED ROOT OF THE BARRIER HEIGHT

$$q = \pm \sqrt{\frac{2m\Delta E}{\hbar^2}}$$

$$\Delta E = 1\text{eV}$$

$$m = \text{free electron} \Rightarrow \frac{1}{q} = 0.2 \text{ nm}$$

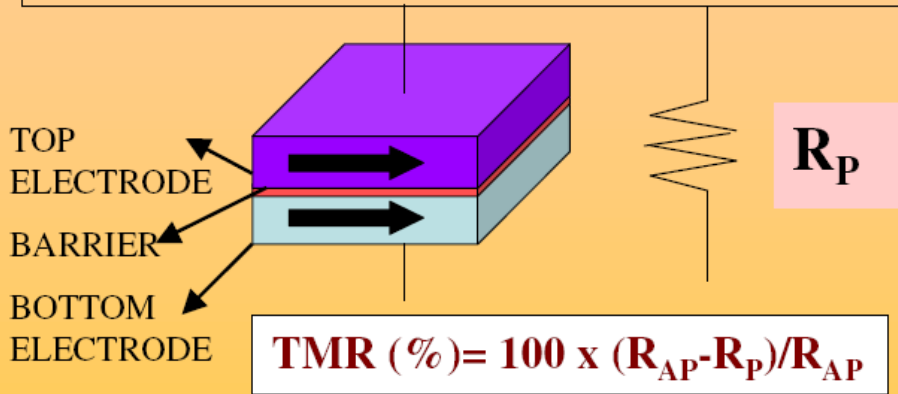
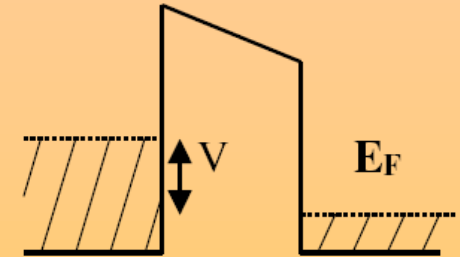
Tunnel barriers must be very thin insulating layers

$$\text{Width} = w < 10 \text{ nm}$$

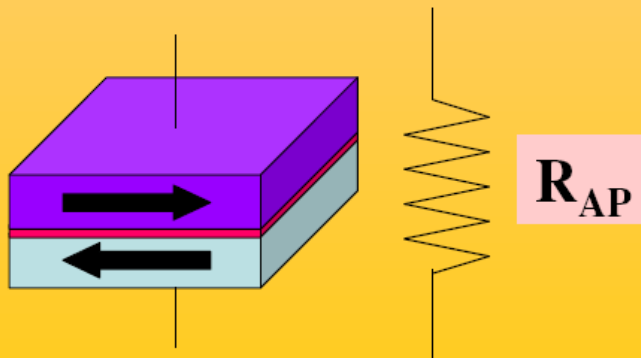
TMR: the basics of magnetic tunnel junctions

⇒ MAGNETIC TUNNEL JUNCTIONS ARE FORMED BY TWO MAGNETIC MATERIALS (ELECTRODES) SEPARATED BY A NANOMETRIC INSULATING LAYER (BARRIER). CONDUCTION TAKES PLACE THROUGH TUNNELLING.

F1 / I / F2

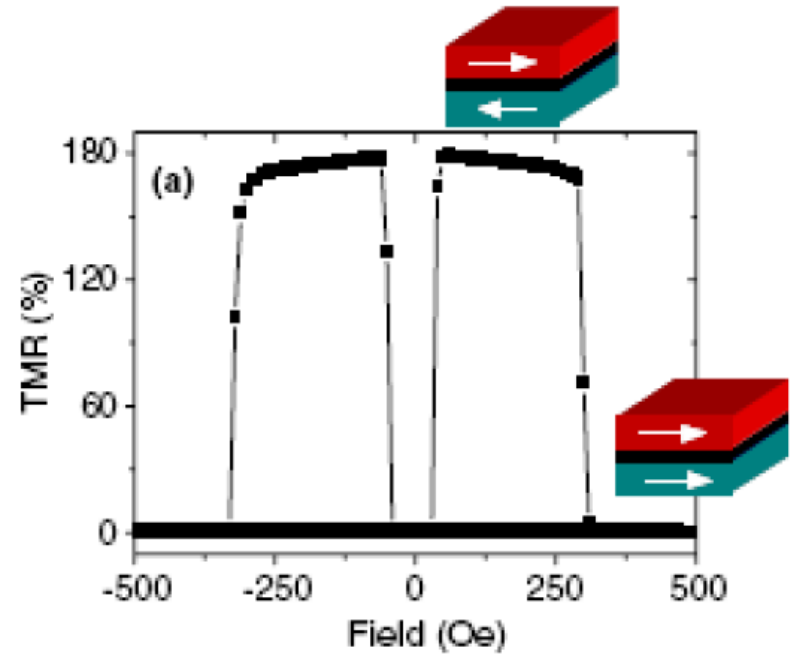


$$\text{TMR (\%)} = 100 \times (R_{AP} - R_P) / R_{AP}$$



$$\text{TMR} = 100 \times \frac{2P_1P_2}{1 + P_1P_2}$$

(Julliere's model)



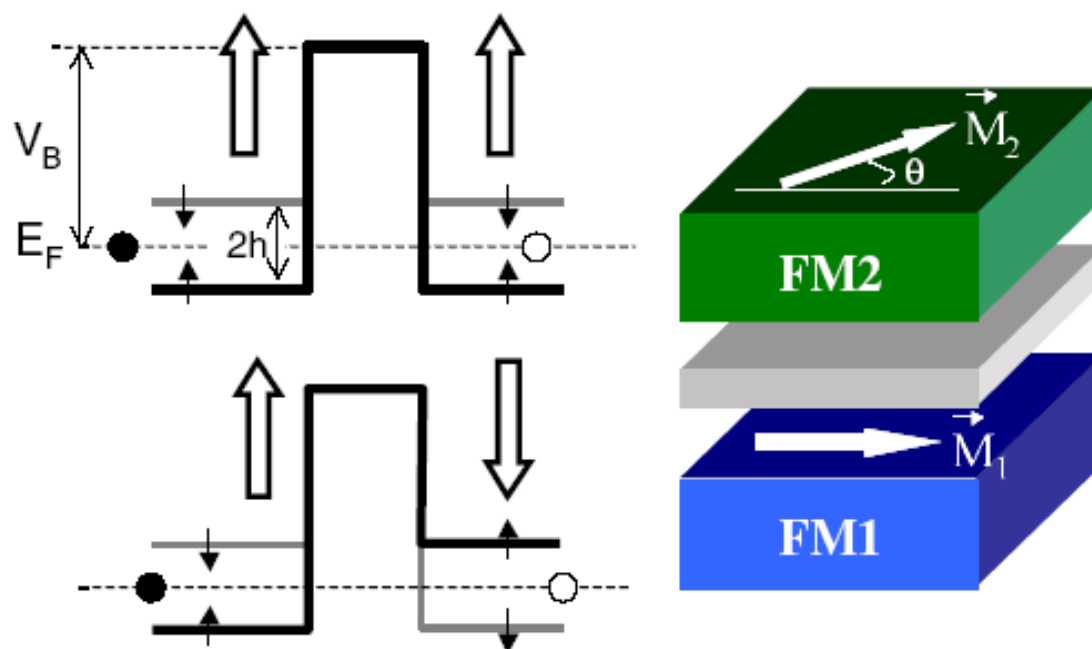


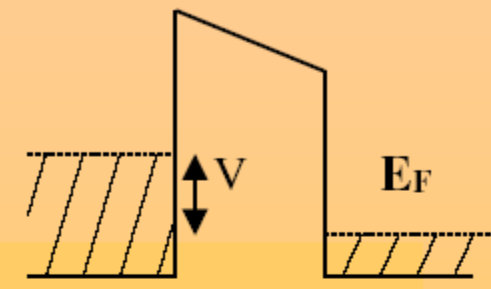
Figure 1. Left panel: potential profile seen by up (thick line) and down spins (thin line) in a magnetic tunnel junction, in the parallel (top) and anti-parallel configurations of magnetization. The exchange splitting in the ferromagnets is $2h$. The rectangular barrier height is V_B , and we denoted the energy of the electrons at the Fermi level by E_F . Right panel: schematic representation of a magnetic tunnel junction composed of two ferromagnetic layers FM1 and FM2 separated by a thin insulating barrier. The magnetization of the two FM layers can be adjusted independently; here we illustrate a configuration where the angle between \vec{M}_1 and \vec{M}_2 is θ .

TMR: the idea behind Julliere's model

F1 / I / F2

$$I(V, E) \propto |T(E)|^2 N_1(E - eV) N_2(E) [f(E - eV) - f(E)]$$

$$\frac{I}{V} \propto |T(E_F)|^2 N_1(E_F) N_2(E_F) \xrightarrow{\text{APROX.}} \frac{I}{V} \propto N_1(E_F) N_2(E_F)$$



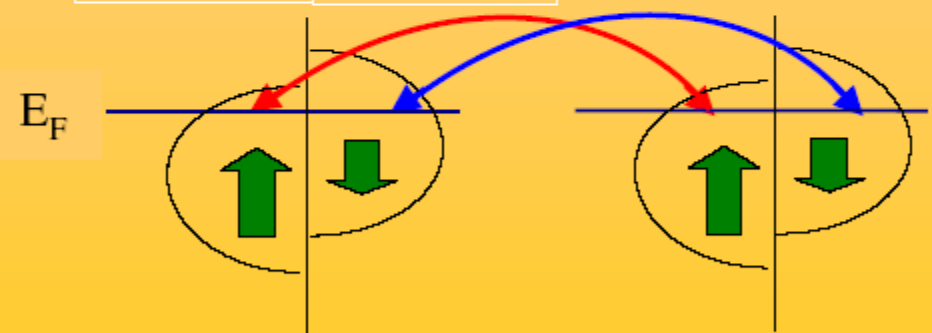
IF THE SPIN IS CONSERVED:

Let $N(E_F) = (1/2) * \text{Total number of electrons at } E_F$

We define an effective spin polarization: $P = [N_{\uparrow}(E_F) - N_{\downarrow}(E_F)] / [N_{\uparrow}(E_F) + N_{\downarrow}(E_F)]$

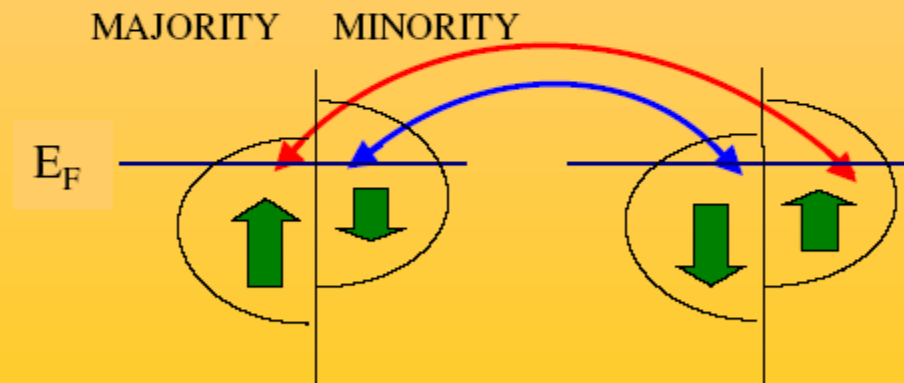
PARALLEL MAGNETIC CONFIGURATION ANTIPARALLEL MAGNETIC CONFIGURATION

MAJORITY MINORITY



$$I_P \propto (1+P_1)(1+P_2) + (1-P_1)(1-P_2)$$

$$= 2(1+P_1P_2)$$



$$I_{AP} \propto (1+P_1)(1-P_2) + (1-P_1)(1+P_2)$$

$$= 2(1-P_1P_2)$$

\Rightarrow **TMR = $(R_{AP} - R_P) / R_{AP} = 1 - (I_{AP} / I_P) = 2P_1P_2 / (1 + P_1P_2)$**

TUNNELING BETWEEN FERROMAGNETIC FILMS

M. JULLIERE

Institut National des Sciences Appliquées, 35031 Rennes Cedex, France

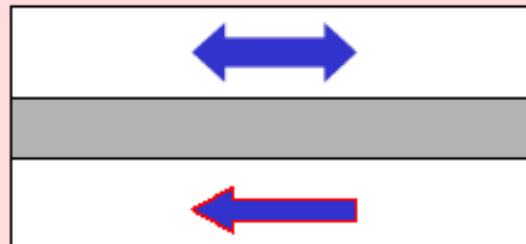
Received 25 June 1975

Fe-Ge-Co junctions conductance $G(V)$ is studied when mean magnetizations of the two ferromagnetic film are parallel or antiparallel. Conductance measurement, in these two cases, is related to the spin polarizations of the conduction electrons.

Development of film deposition techniques

Trilayer : better characterisation of electrodes and control of magnetisation

R changes by 14% at low temperature depending on the magnetic configuration

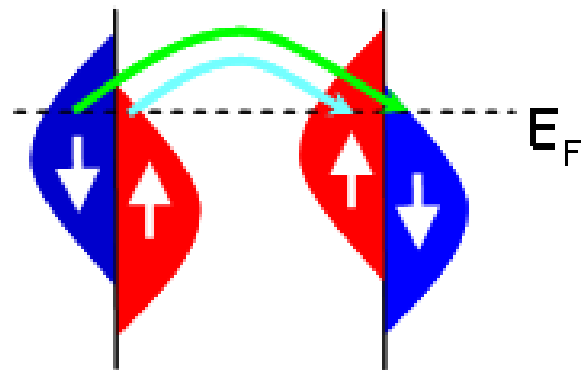
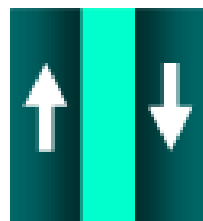
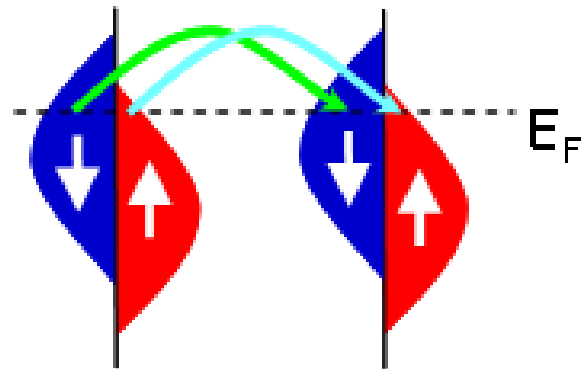
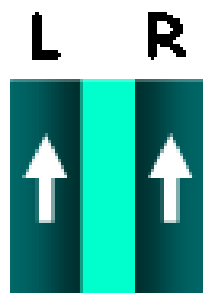


Co

Ge (10-15nm) +dry oxygen

Fe

L. Ranno, Spin dependent tunnel transport and spin polarization, 2003, Brasov.Romania. Summer School



Large Magnetoresistance at Room Temperature in Ferromagnetic Thin Film Tunnel Junctions

J. S. Moodera, Lisa R. Kinder, Terrilyn M. Wong, and R. Meservey

Francis Bitter National Magnet Laboratory, Massachusetts Institute of Technology, Cambridge, Massachusetts 02139

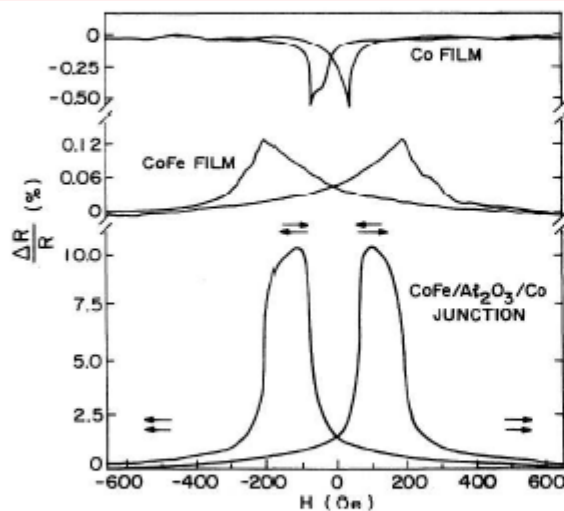
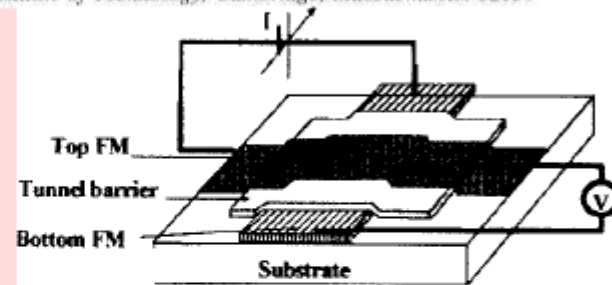


FIG. 2. Resistance of CoFe/Al₂O₃/Co junction plotted as a function of H in the film plane, at 295 K. Also shown is the variation in the CoFe and Co film resistance. The arrows indicate the direction of M in the two films (see text).



200 μm x 300 μm

11.8% at 300 K

24% at 24 K

$\phi=1.9$ eV and $t=1.6$ nm

$V_{50\%}=200\text{mV}$

And also Miyazaki, Tezuka JMMM 139 (1995) L231

Jullière 's model (1975)

Not magnetisation

BUT Polarisation of electrodes is the parameter

$$P = \frac{N_{\uparrow}(E_F) - N_{\downarrow}(E_F)}{N_{\uparrow}(E_F) + N_{\downarrow}(E_F)}$$

$$N_{i\uparrow} = \frac{N_i(1+P_i)}{2} \quad N_{i\downarrow} = \frac{N_i(1-P_i)}{2}$$

Assume : No spin-flip transition across the barrier at low voltage

➔ 2 parallel channels (spin up and spin down)

Conductance is the sum of spin up and down conductances

Conductance is proportional to the density of state (d.o.s.) 1 and d.o.s. 2

$$G_{spin\ i} = G_0 N_{spin\ i\ electrode\ 1}(E_F) N_{spin\ i\ electrode\ 2}(E_F)$$

$$G_{\uparrow\uparrow} = G_0 N_{1\uparrow}(E_F) N_{2\uparrow}(E_F) + G_0 N_{1\downarrow}(E_F) N_{2\downarrow}(E_F)$$

$$G_{\uparrow\downarrow} = G_0 N_{1\uparrow}(E_F) N_{2\downarrow}(E_F) + G_0 N_{1\downarrow}(E_F) N_{2\uparrow}(E_F)$$

Jullière 's model

(M. Jullière, Phys. Lett. 54 A, 225 (1975))

TMR ratio :

$$G_{\uparrow\downarrow} + G_{\uparrow\uparrow} = G_0 N_1 N_2$$

$$G_{\uparrow\uparrow} - G_{\uparrow\downarrow} = G_0 N_{1\uparrow} N_2 P_2 - G_0 N_{1\downarrow} N_2 P_2 = G_0 N_1 P_1 N_2 P_2$$

$$\frac{G_{\uparrow\uparrow} - G_{\uparrow\downarrow}}{G_{\uparrow\uparrow} + G_{\uparrow\downarrow}} = P_1 P_2 \quad \text{or} \quad \frac{G_{\uparrow\uparrow} - G_{\uparrow\downarrow}}{G_{\uparrow\uparrow}} = \frac{2P_1 P_2}{1 + P_1 P_2}$$

(pick your definition)

$$\frac{R_{\uparrow\uparrow} - R_{\uparrow\downarrow}}{R_{\uparrow\uparrow}} = \frac{-2P_1 P_2}{1 - P_1 P_2}$$

Does depend on P_i

Does not depend on the barrier (height, width)

because of assumption about G_0

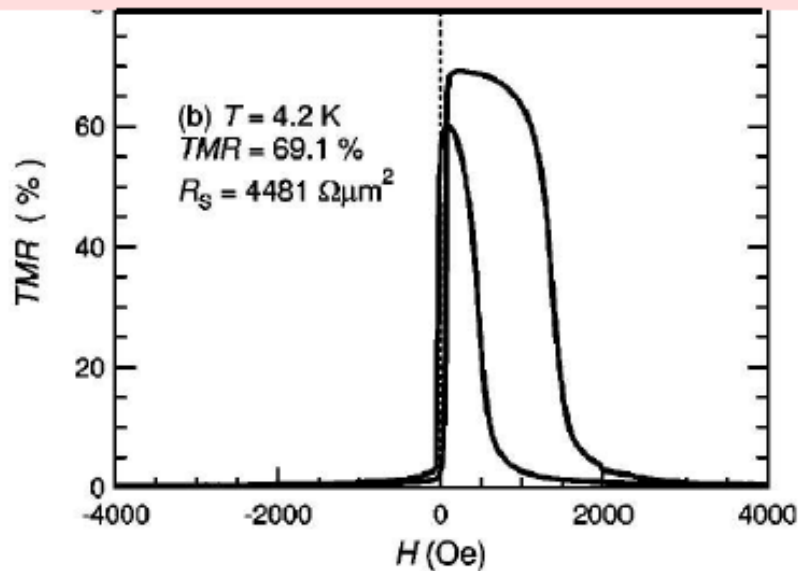
i.e. no spin dependence of transmission

Fe/a-Ge/Co (Jullière)

Exp : TMR=14%

Theor : $P_{\text{Co}}34\% + P_{\text{Fe}}44\%$

TMR 26%



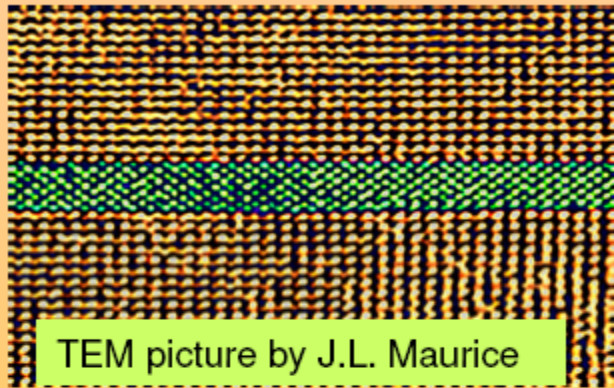
69.1% at 4.2 K

From Jullière 's formula

$P_{\text{CoFe}}=50.7\%$
similar to expected

CoFe TMR junction (Tohoku 2000)

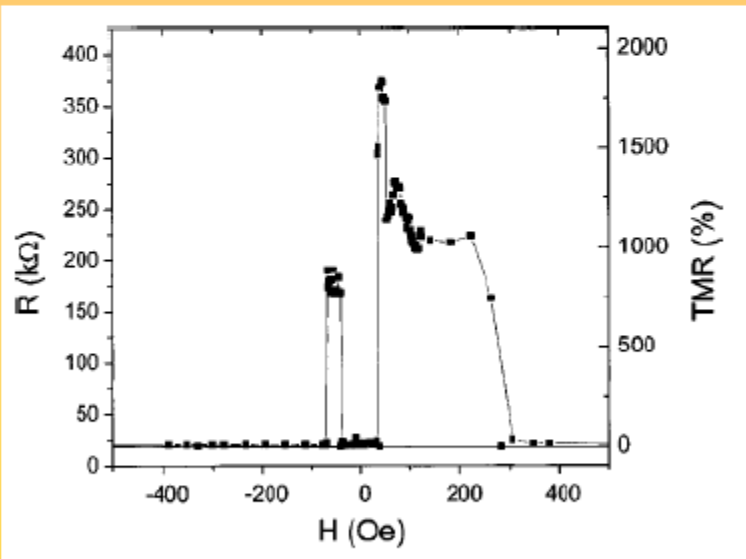
MANGANITE-based MTJs



$\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3$

SrTiO_3

$\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3$

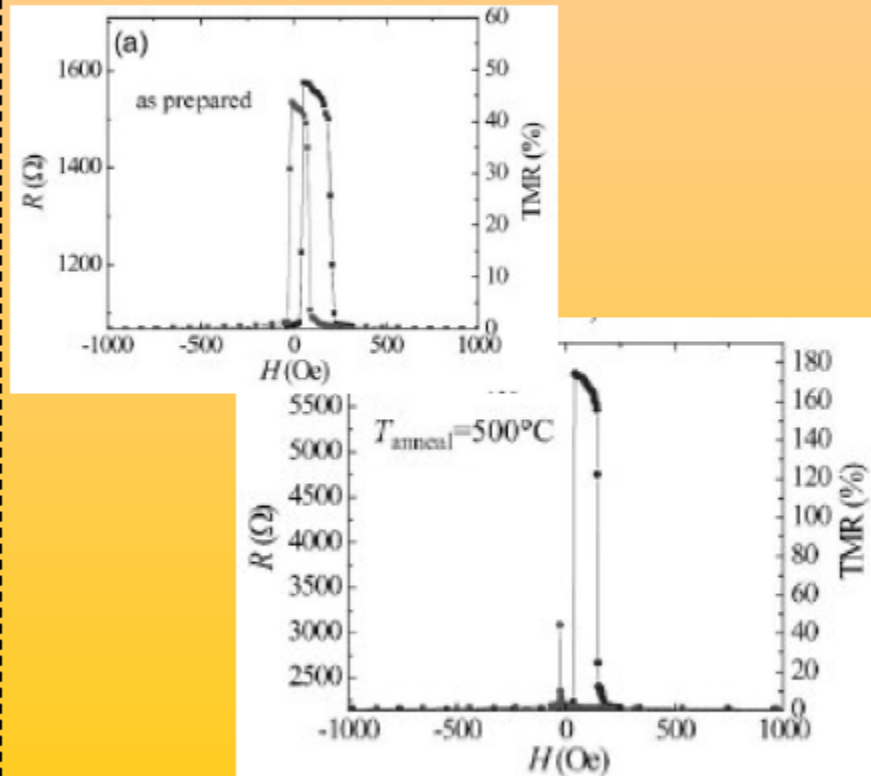


MR > 1500% at 5K, which corresponds to $P=0.95$ (however, the MR vanishes at 300 K)

Bowen et al., Appl. Phys. Lett. 82, 233 (2003)

HEUSLER ALLOYS-based MTJs

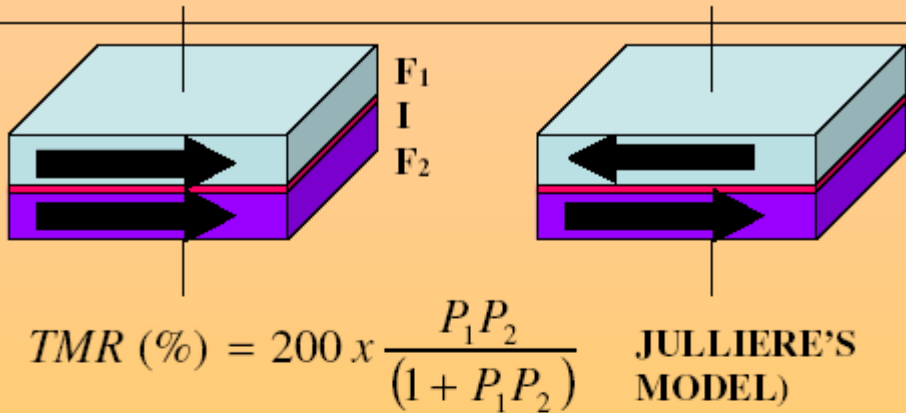
The MTJs with a stacking structure of $\text{Co}_2\text{FeAl}_{0.5}\text{Si}_{0.5}$ (30 nm)/MgO (t_{MgO} nm)/ $\text{Co}_2\text{FeAl}_{0.5}\text{Si}_{0.5}$ (5 nm)/ $\text{Co}_{75}\text{Fe}_{25}$ (3 nm)/ $\text{Ir}_{22}\text{Mn}_{78}$ (15 nm)/capping layer (Ta) were fabricated on a Cr-buffered MgO(001) substrate. The films were pre-



MR = 175% at room temperature, which corresponds to $P=0.68$

Tezuka et al., Appl. Phys. Lett. 89, 252508 (2006)

TMR: understanding the TMR effect



MAJORITY
e- "SPIN UP"

MINORITY
e- "SPIN DOWN"



What P value is the right one to be included in Julliere's formula?

$$P = \frac{N(E_F)_{\uparrow} - N(E_F)_{\downarrow}}{N(E_F)_{\uparrow} + N(E_F)_{\downarrow}} ?$$

THE EXAMPLE OF COBALT

PHOTOEMISSION: INFORMATION ON

$$P = \frac{N(E_F)_{\uparrow} - N(E_F)_{\downarrow}}{N(E_F)_{\uparrow} + N(E_F)_{\downarrow}}$$

P(Co) < 0

TUNNEL JUNCTIONS F/I/S:

INFORMATION ON P(Co) IN TUNNELLING

P(Co) > 0 WITH Al₂O₃ BARRIER

[experiments carried out by Tedrow and Meservey: see review in Phys. Repts. 238 (1994) 173]

* **"s-type" BANDS** \Rightarrow lower density of states, positively polarized, more delocalized electrons

* **"d-type" BANDS** \Rightarrow higher density of states, negatively polarized, more localized electrons

TMR: understanding the TMR effect

DESIGNED EXPERIMENT: $\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3$ / I / Co (I = SrTiO_3 , Al_2O_3 , CeO_2)

(experiments performed in Orsay with A. Fert's Group)

The experiment aims at probing the spin polarization of Co when using different barriers in tunnel junctions, which can be related to the preferential tunnelling of "s-type" or "d-type" electrons from Co.

$$100 * \frac{(R_{AP} - R_P)}{R_P} = TMR(\%) = 200x \frac{P_1 P_2}{(1 + P_1 P_2)}$$

$$\left\{ \begin{array}{l} * P(\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3) \approx +100\% \\ * P(\text{Co}) = ? \end{array} \right.$$

$\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3$

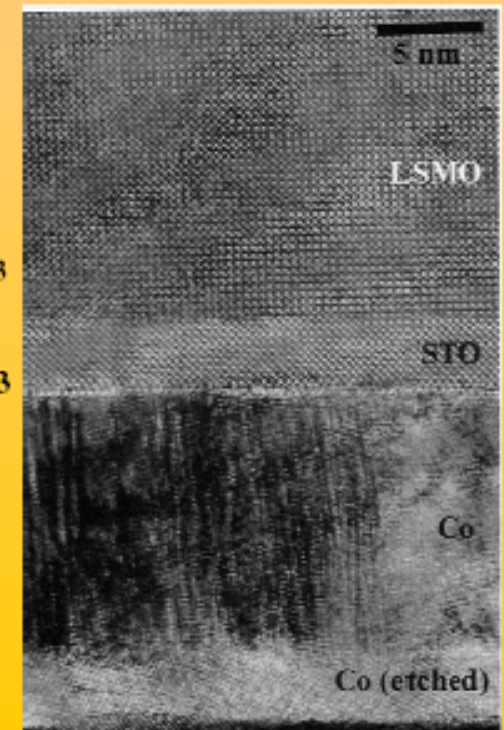
SrTiO_3

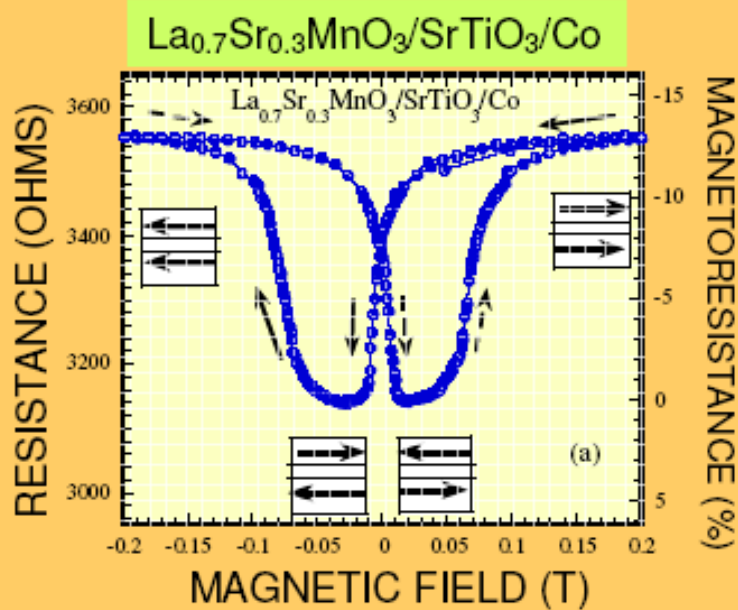
Co

If $P(\text{Co}) > 0 \Rightarrow TMR(\%) > 0$

If $P(\text{Co}) < 0 \Rightarrow TMR(\%) < 0$

TEM IMAGE BY J.L. MAURICE

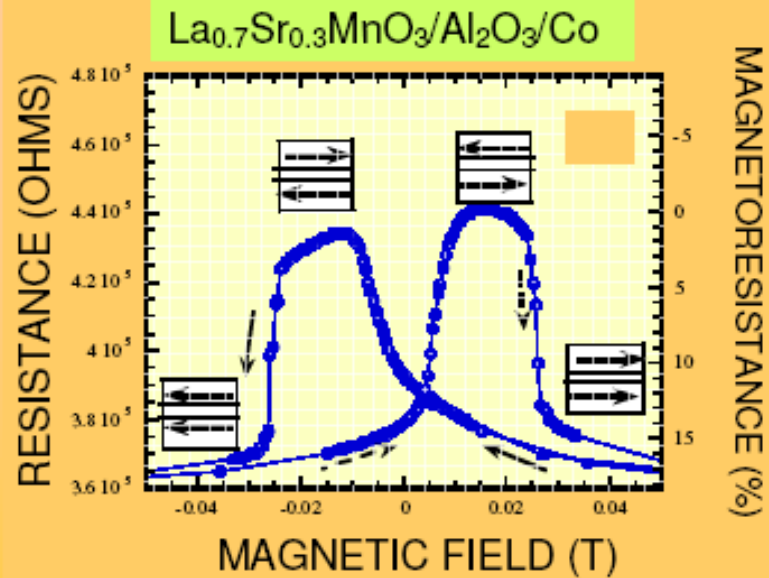




INVERSE TMR

$$R_{AP} < R_P$$

P(Co) IS NEGATIVE



NORMAL TMR

$$R_P < R_{AP}$$

P(Co) IS POSITIVE

$$\text{TMR} \propto \frac{P_{(\text{LSMO})}P_{(\text{Co})}}{[1+P_{(\text{LSMO})}P_{(\text{Co})}]}; \text{ with } P_{(\text{LSMO})} > 0$$

J.M. De Teresa et al., Phys. Rev. Lett. 82 (1999) 4288; J.M. De Teresa et al., Science 286 (1999) 507; Hayakawa et al., J. Appl. Phys. 91 (2002) 8792; Hayakawa et al., Jpn J. Appl. Phys. 41 (2002) 1340

if the insulator has **d** electrons the Co **d** structure is dominant. For the measurement we can deduce with **STO** the **d** tunneling is favored and with **ALO** the **s** structure.

$$P = \frac{q^2 - k_{F\uparrow}k_{F\downarrow}}{q^2 + k_{F\uparrow}k_{F\downarrow}} \frac{k_{F\uparrow} - k_{F\downarrow}}{k_{F\uparrow} + k_{F\downarrow}} \quad q = \pm \sqrt{\frac{2m\Delta E}{\hbar^2}}$$

High barrier

$$P = \frac{q^2}{q^2} \cdot \frac{k_{F\uparrow} - k_{F\downarrow}}{k_{F\uparrow} + k_{F\downarrow}} = \frac{k_{F\uparrow} - k_{F\downarrow}}{k_{F\uparrow} + k_{F\downarrow}}$$

Free electrons

$$DOS(E) = \frac{m}{\hbar^3 \pi^2} \sqrt{2mE} = \frac{mk}{\hbar^2 \pi^2} \propto k$$

$$P = \frac{N_{\uparrow}(E_F) - N_{\downarrow}(E_F)}{N_{\uparrow}(E_F) + N_{\downarrow}(E_F)} \quad \text{Back to Jullière's formula}$$

Improved models :

Bratkovsky :

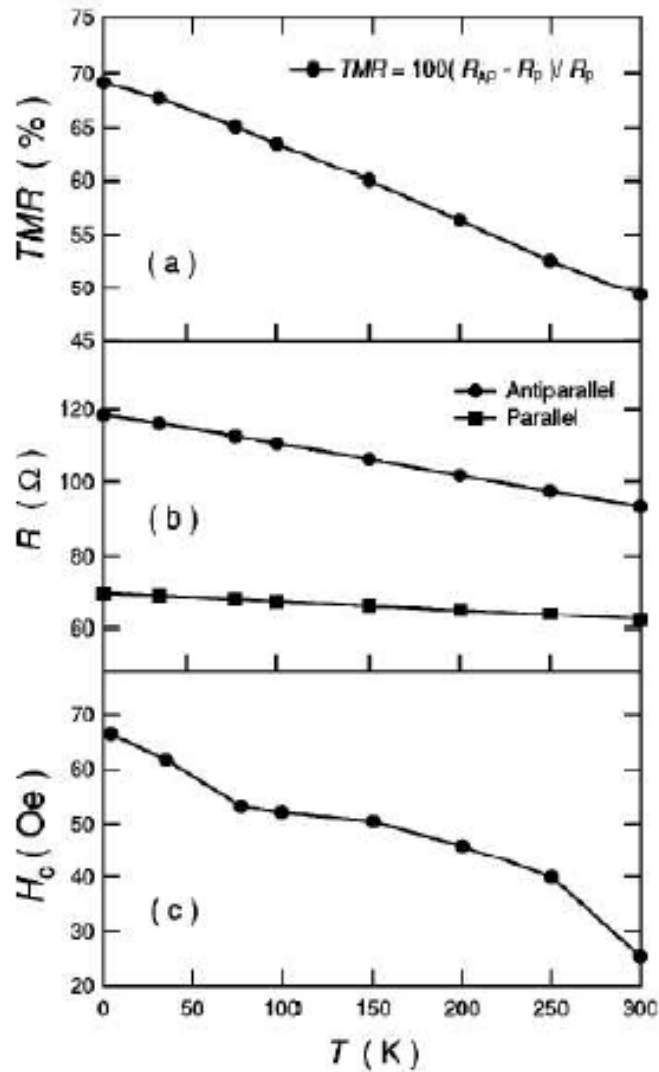
Correction to Slonczewski's model (different effective mass in the barrier)

$$P = \frac{q^2 - m_b^2 \cdot k_{F\uparrow} k_{F\downarrow}}{q^2 + m_b^2 \cdot k_{F\uparrow} k_{F\downarrow}} \frac{k_{F\uparrow} - k_{F\downarrow}}{k_{F\uparrow} + k_{F\downarrow}} \quad q = \pm \sqrt{\frac{2m_b \Delta E}{\hbar^2}}$$

$m_b/m=0.4$ for Fe/Al₂O₃

Ab initio band structure calculations :

to get the band structure close to the interface

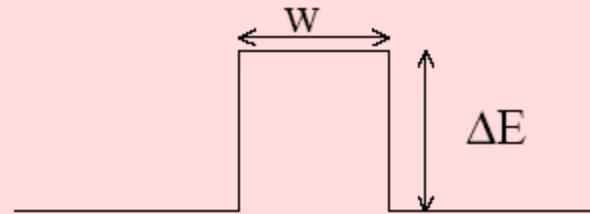


TMR temperature dependence

Resistance Temperature dependence

Miyazaki group (Tohoku) APL 2000

Temperature dependence of the barrier transmission
Going from 0 Kelvin to 300 Kelvin

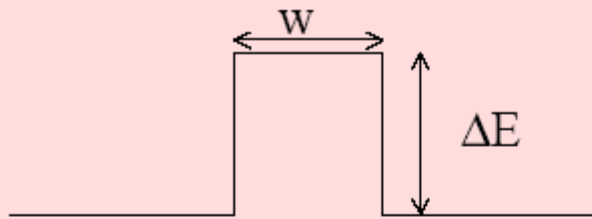


Wavevector in the barrier (evanescent wave)

$$q = \sqrt{\frac{2m\Delta E}{\hbar^2}}$$

Conductance \propto *Transmission*

$$\text{Transmission} = T \propto e^{-2qw}$$



$$q = \sqrt{\frac{2m\Delta E}{\hbar^2}}$$

$$\text{Transmission} = T \propto e^{-2qw}$$

$$\frac{dT}{T} = d(-2qw) = -2w \cdot dq = -wq \frac{d\Delta E}{\Delta E}$$

$$q = 1 \text{ \AA}^{-1}, w = 1 \text{ nm},$$

$$\Delta E = 2 \text{ eV}, d\Delta E = kT = 25 \text{ meV}$$

$$\frac{\Delta T}{T} = \frac{\Delta G}{G} = \frac{\Delta R}{R} = 12.5\%$$

Temperature dependence of TMR

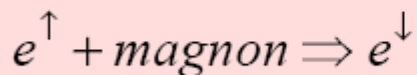
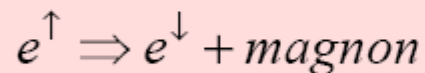
Different contributions may rule this behaviour :

- Polarisation is related to magnetisation

$$M(T) = M_s(T)(1 - \alpha T^{3/2})$$

$$P(T) = P_s(T)(1 - \alpha T^{3/2})$$

- Inelastic processes can appear

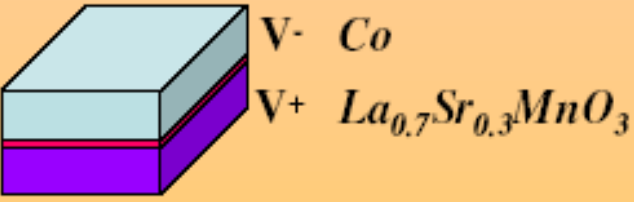
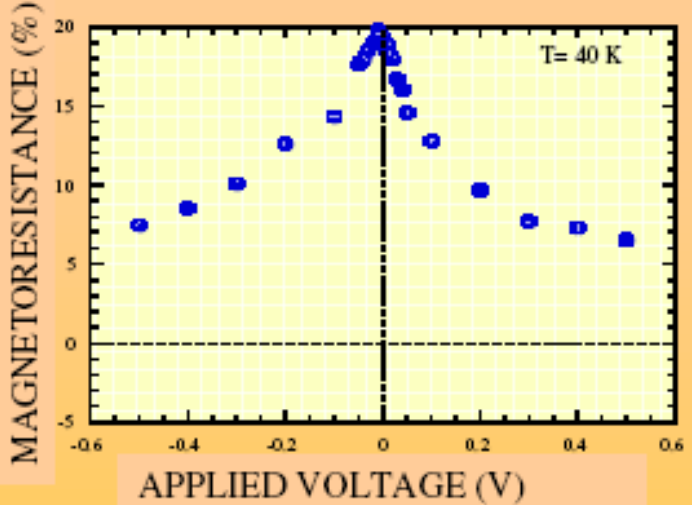


Opens a spin-flip conductance channel
conductance increases
TMR decreases

- Surface magnetisation is less robust to thermal fluctuations

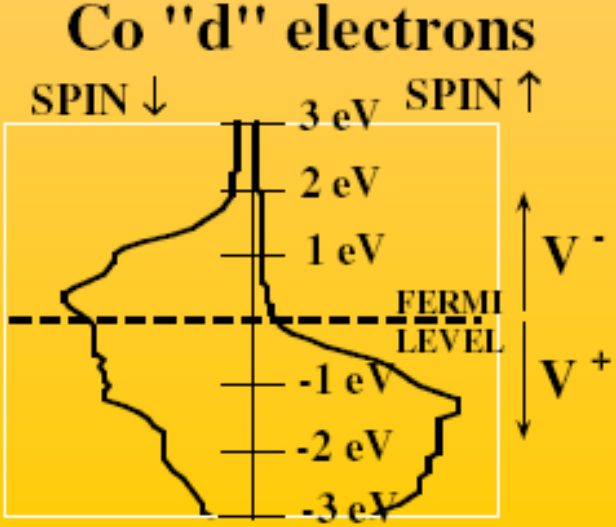
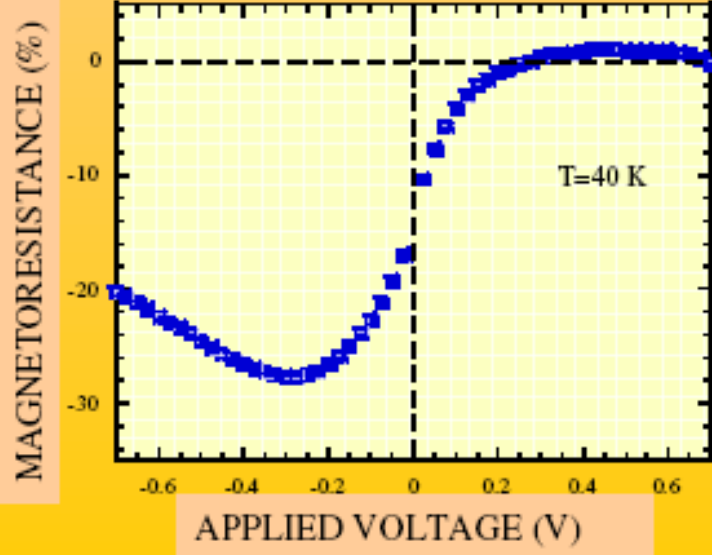
No general results, depends on the studied system (T_c , surface state ...)

*DEPENDENCE OF THE TUNNEL
MAGNETORESISTANCE WITH VOLTAGE*

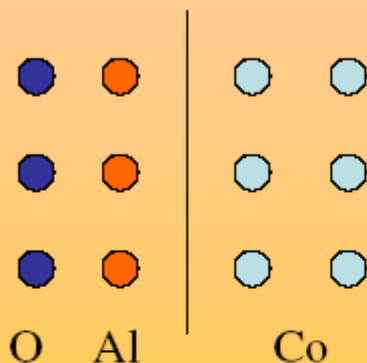


I = Al₂O₃: CURRENT BY
"s-type" ELECTRONS

I = SrTiO₃: CURRENT BY
"d-type" ELECTRONS

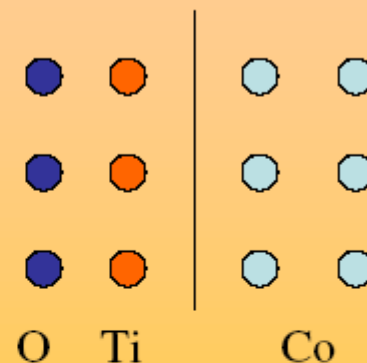


Al₂O₃/Co INTERFACE



sp-d BONDING
Selection of "s" electrons

SrTiO₃/Co INTERFACE

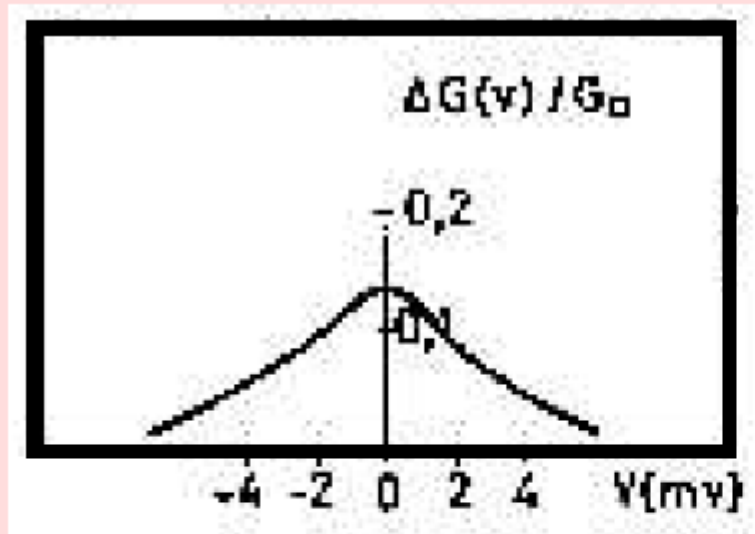


d-d BONDING
Selection of "d" electrons

 **THE INTERFACE CONTROLS THE STARTING POINT OF THE EVANESCENT WAVE IN THE BARRIER**

(related theoretical articles supporting these experiments: Tsymbol et al., *J. Phys. Condens. Matter.* 9 (1997) L411; Stoeffler, *J. Phys. Condens. Matter.* 16 (2004) 1603; Oleinik et al., *Phys. Rev. B* 65 (2002) 020401; Velev et al., *Phys. Rev. Lett.* 95 (2005) 216601)

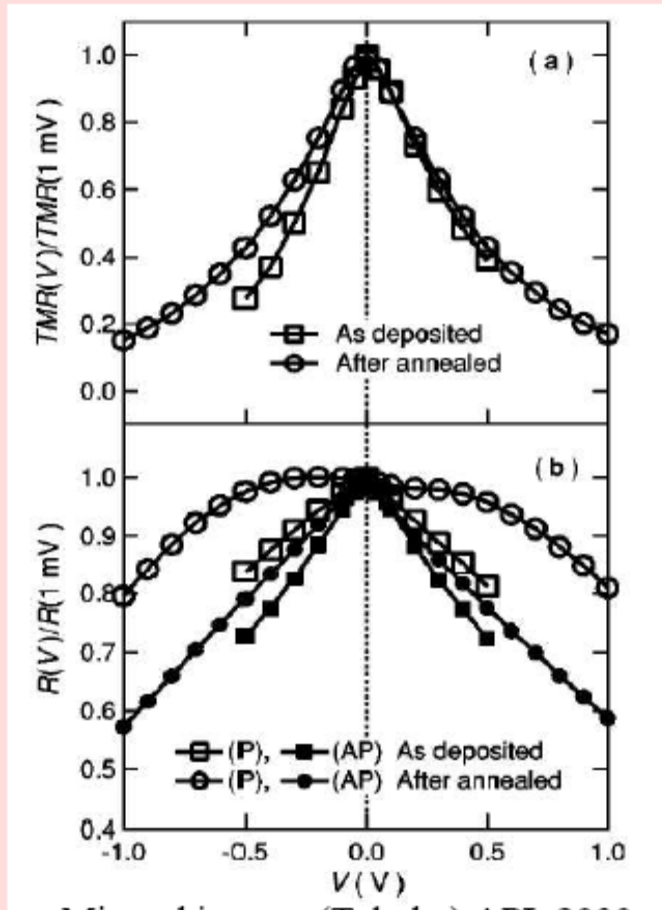
Voltage dependence of TMR



$$\text{TMR}_{50\%} = 3\text{mV}$$

50% MR at 3mV

Jullière, Phys. Lett. 1975



Miyazaki group (Tohoku) APL 2000

TMR - bias voltage dependence
50% decrease TMR for 400mV

R - bias voltage dependence

At large bias voltages, hot electrons are introduced in the second electrode : $0.1 \text{ V} = 1200 \text{ Kelvin}$

Inelastic processes can be activated

$$e^{\uparrow} \Rightarrow e^{\downarrow} + \text{magnon}$$

$$e^{\uparrow} + \text{magnon} \Rightarrow e^{\downarrow}$$

Opens a spin-flip conductance channel

TMR decreases with V

The voltage decrease depends on experimental systems and years

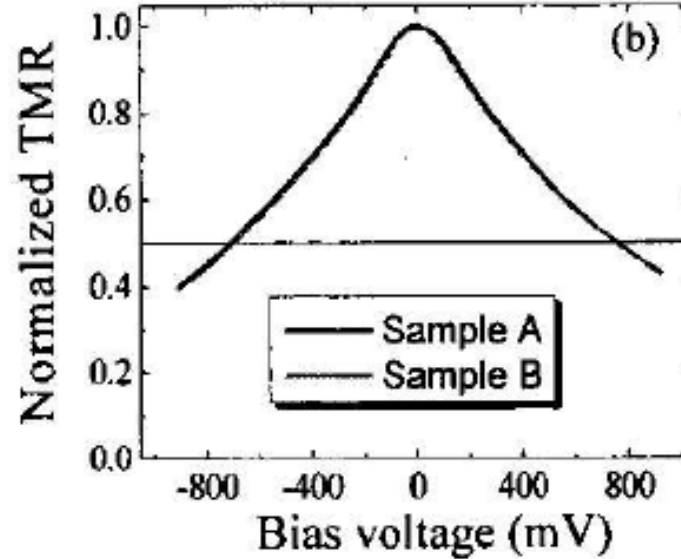
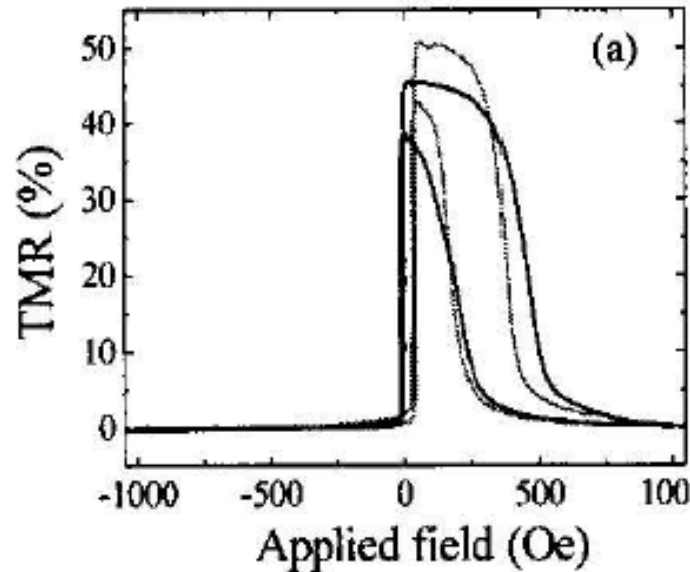
$$1975 : \text{TMR}_{50\%} = 2 \text{ mV}$$

$$1995 : \text{TMR}_{50\%} = 200 \text{ mV}$$

$$2000 : \text{TMR}_{50\%} = 450 \text{ mV}$$

$$2003 : \text{TMR}_{50\%} > 1000 \text{ mV}$$

May be due to non perfect samples, which improve with time



Epitaxial NiFe electrode : 50 % decrease of TMR at **750 mV**

Yu et al. APL 2003

A few words about

The insulating barrier

Making the barrier

Good recipe #1

Aluminium Film (0.7-2 nm)
+ thermal oxidation in oxygen atmosphere or air

Good recipe #2

Aluminium Film + oxygen plasma

a

Giant room-temperature magnetoresistance in single-crystal Fe/MgO/Fe magnetic tunnel junctions

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¹NanoElectronics Research Institute, National Institute of Advanced Industrial Science and Technology (AIST), Tsukuba, Ibaraki 305-8568, Japan
²PRESTO, Japan Science and Technology Agency, Kawaguchi, Saitama 332-0012, Japan

nature materials | VOL 3 | DECEMBER 2004 | www.nature.com/naturematerials

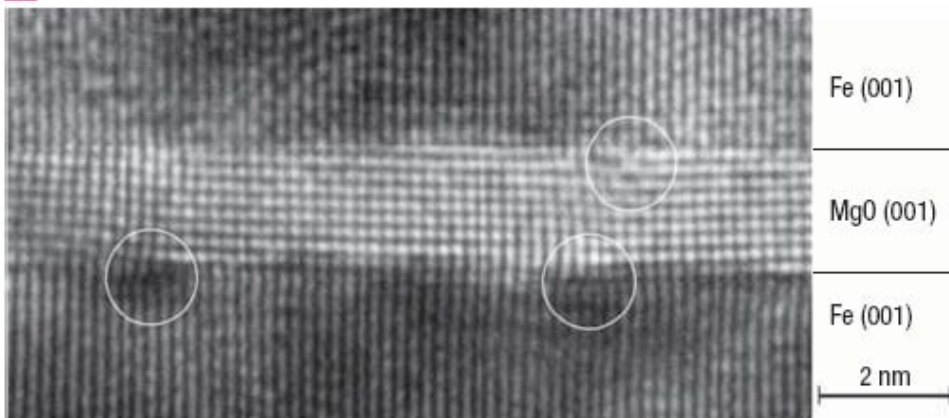
b

Figure 1 TEM images of a single-crystal MTJ with the Fe(001)/MgO(001)(1.8 nm)/Fe(001) structure. **b** is a magnification of **a**. The vertical and horizontal directions respectively correspond to the MgO[001] (Fe[001]) axis and MgO[100] (Fe[110]) axis. Lattice dislocations are circled. The lattice spacing of MgO is 0.221 nm along the [001] axis and 0.208 nm along the [100] axis. The lattice of the top Fe electrode is slightly expanded along the [110] axis.

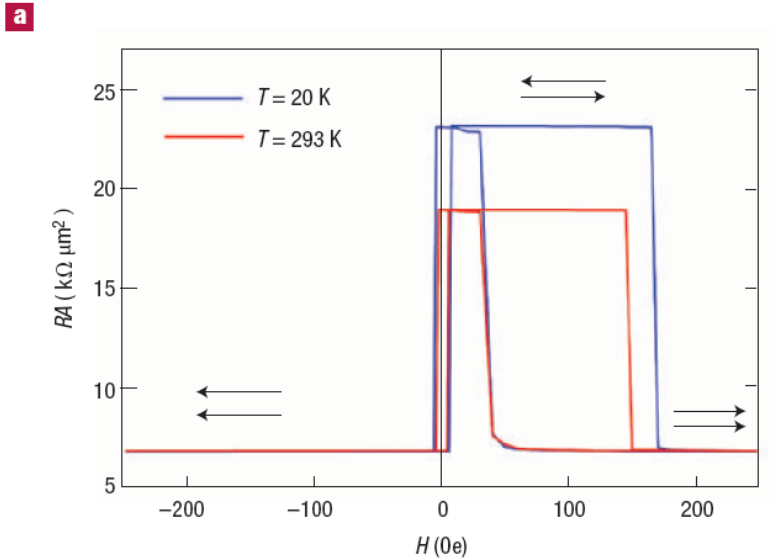
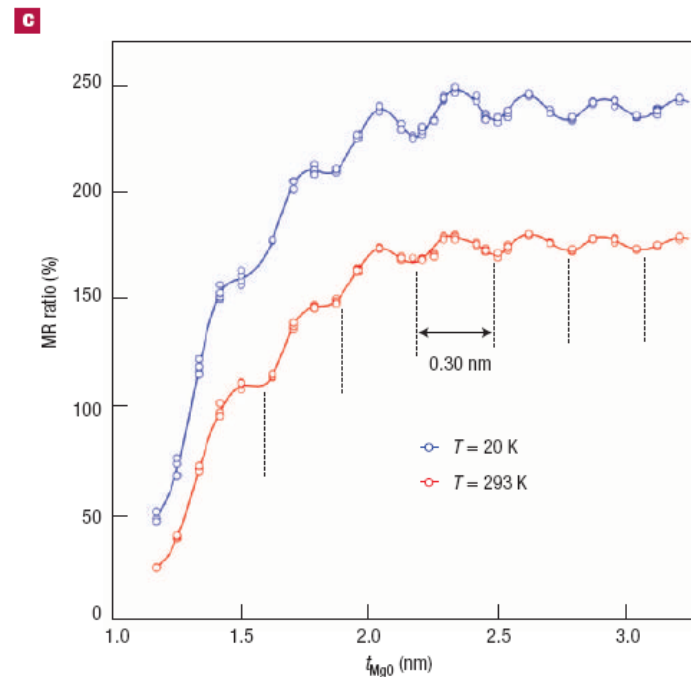
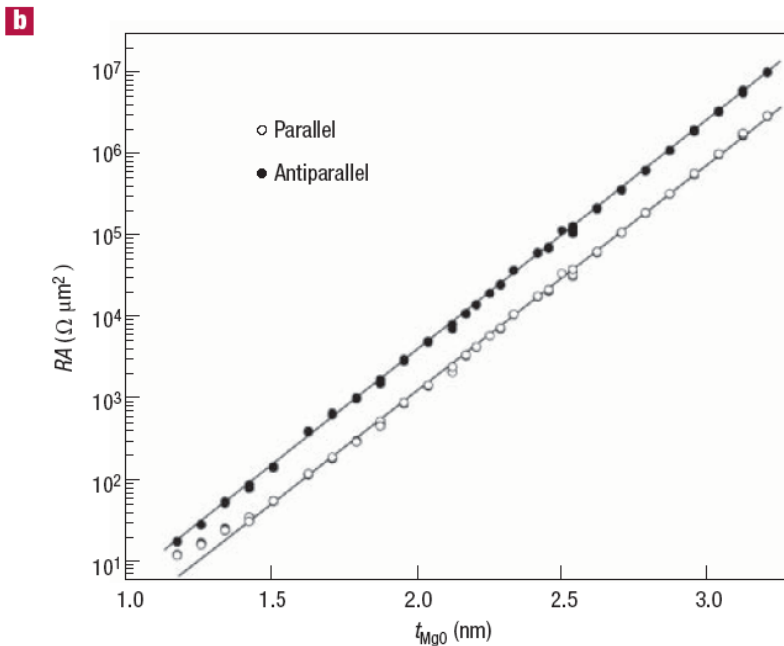
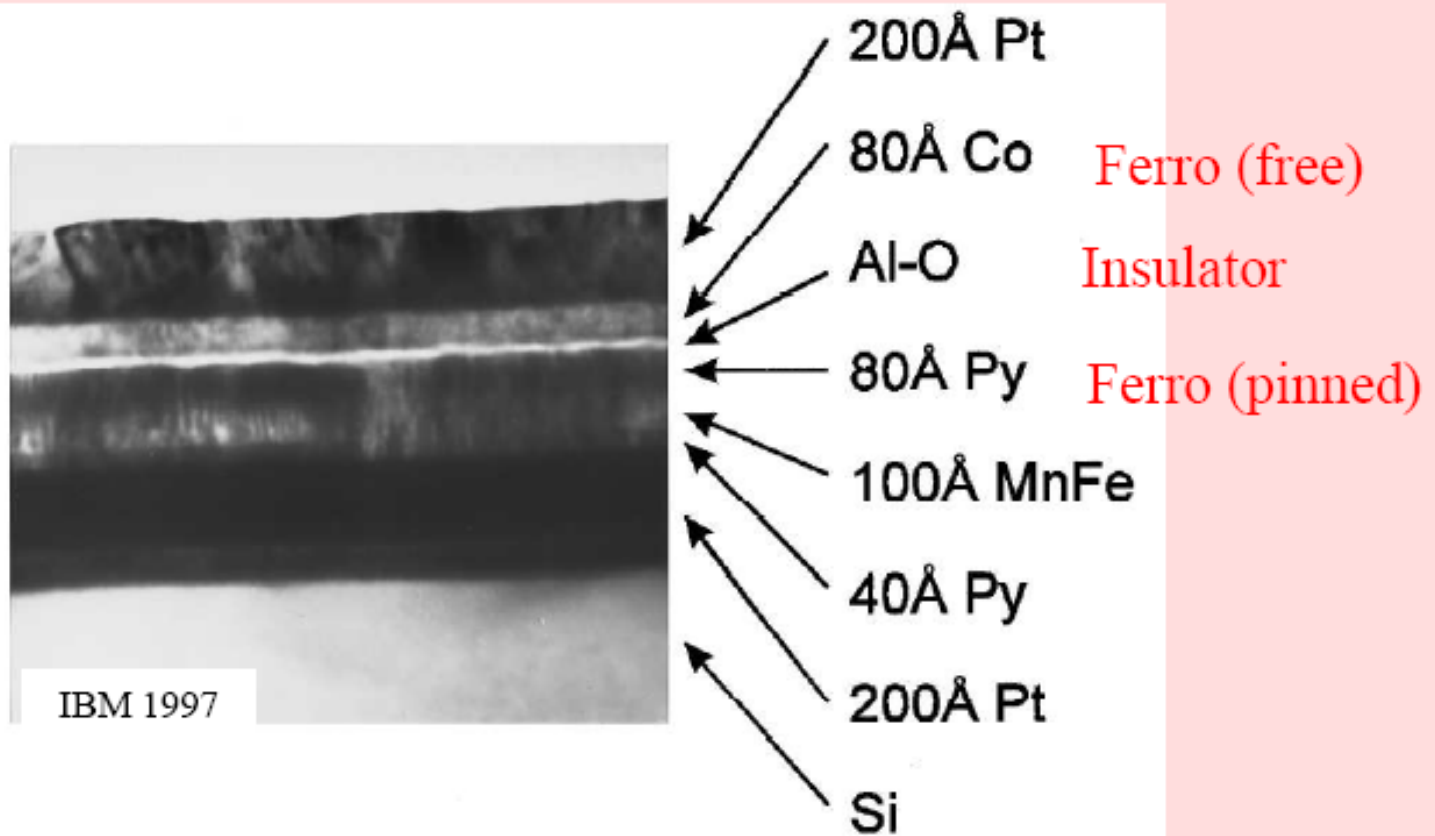


Figure 2 Tunnel magnetoresistance of Fe(001)/MgO(001)/Fe(001) junctions. **a**, Magnetoresistance curves (measured at a bias voltage of 10 mV) at $T = 293 \text{ K}$ and 20 K (MgO thickness $t_{\text{MgO}} = 2.3 \text{ nm}$). The resistance–area product RA plotted here is the tunnel resistance for a $1 \times 1 \mu\text{m}^2$ area. Arrows indicate magnetization configurations of the top and bottom Fe electrodes. The MR ratio is 180% at 293 K and 247% at 20 K . **b**, RA at $T = 20 \text{ K}$ (measured at a bias voltage of 10 mV) versus t_{MgO} . Open and filled circles represent parallel and antiparallel magnetic configurations. The scale of the vertical axis is logarithmic. **c**, MR ratio at $T = 293 \text{ K}$ and 20 K (measured at a bias voltage of 10 mV) versus t_{MgO} .



Magnetic Tunnel Junction



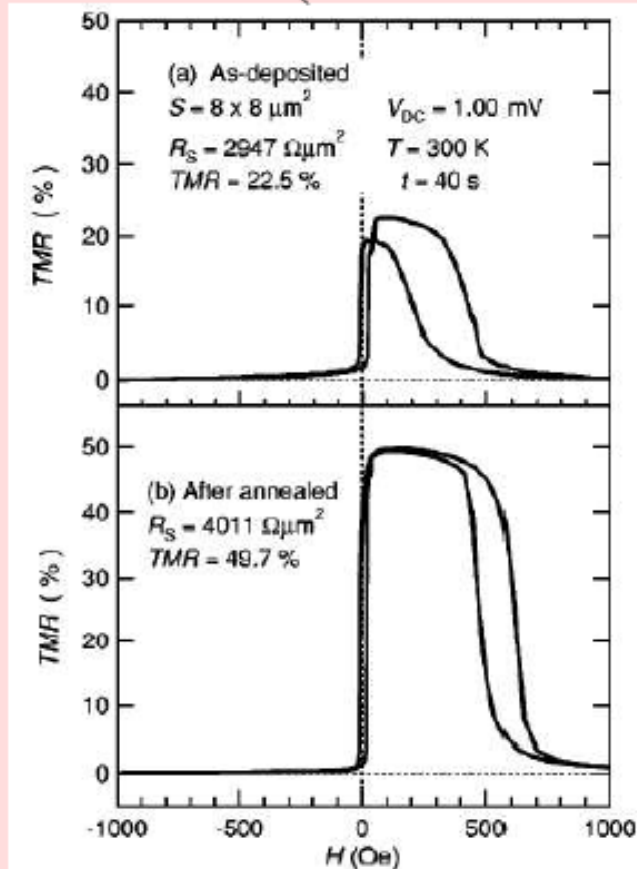
Same technical solutions as GMR structures to get 2 different coercive fields
i.e. well defined parallel and antiparallel states.

Hard - Soft materials (Co - NiFe)

Different shape anisotropies for both electrodes

Pinning to AF layer (MnFe) or Artificial AF layer (Co/Ru/Co)

Best present TMR junctions : 50% Room temperature (non exotic materials)



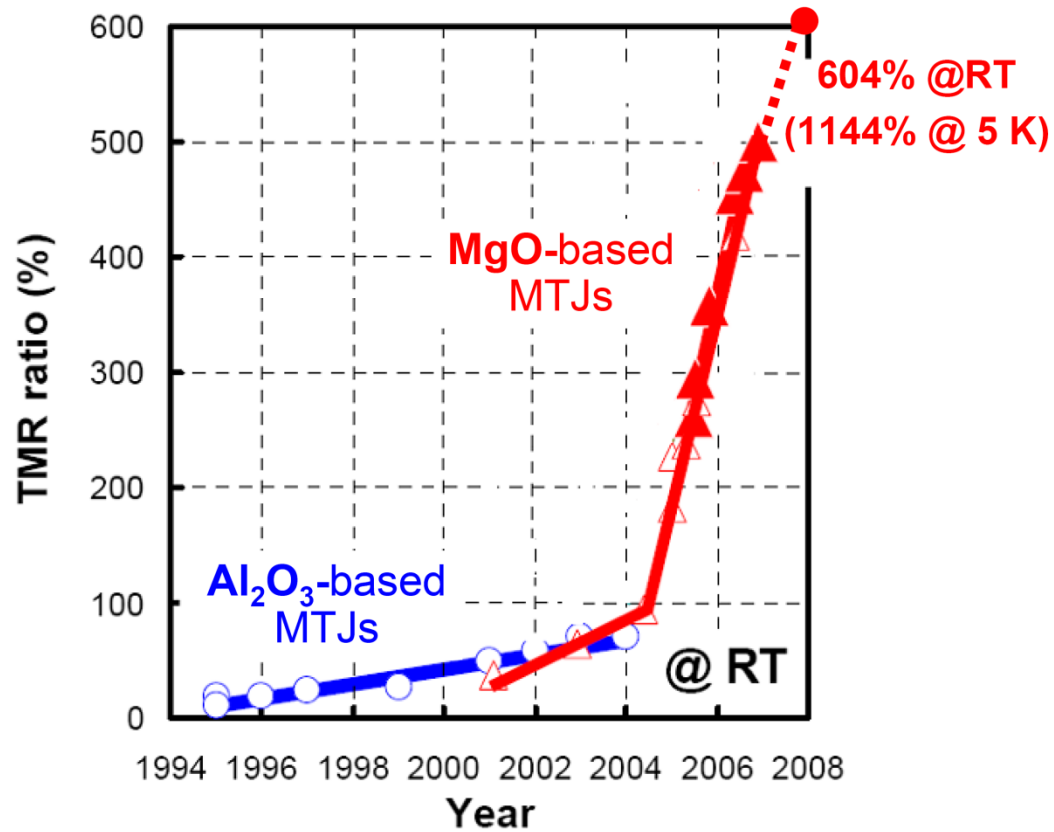
Miyazaki group (Tohoku) APL 2000

Ta (5 nm)/
 Ni₇₉Fe₂₁ (3 nm)/
 Cu (20 nm)/
 Ni₇₉Fe₂₁ (3 nm)/
 Ir₂₂Mn₇₈ (10 nm)/
 Co₇₅Fe₂₅ (4 nm)/
 Al (0.8 nm)-oxide/
 Co₇₅Fe₂₅ (4 nm)/
 Ni₇₉Fe₂₁ (20 nm)/
 Ta (5 nm)

Pinned layer
 Free layer

Summary of TMR record values in MTJs

TMR ratio of MTJs

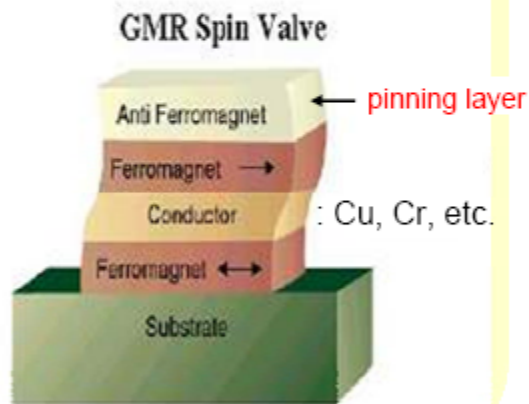


GMR vs. TMR

GMR

(Giant MagnetoResistance)

- Spin Valve

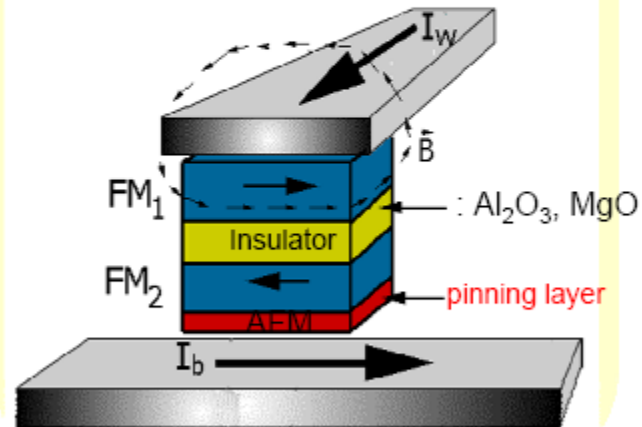


Short spin relaxation length
→ Low GMR (~ 20%)

TMR

(Tunnelling MagnetoResistance)

- MTJ (Magnetic Tunnel Junction)

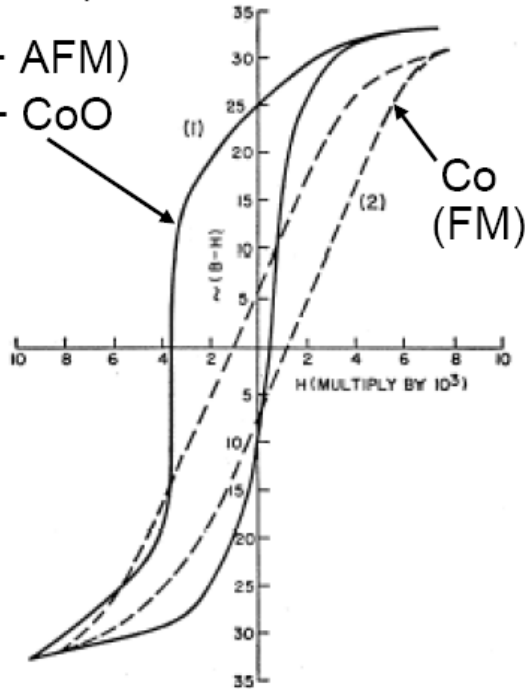


Long spin relaxation length
→ High TMR (< 600%)

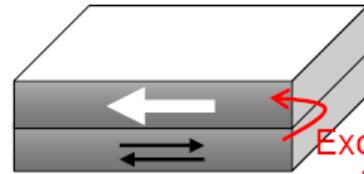
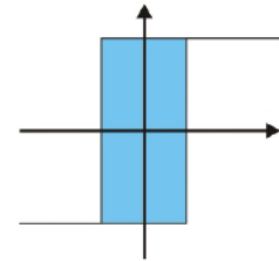
Exchange bias in FM/AFM system

Oxygen-coated Co particles

(FM + AFM)
Co + CoO



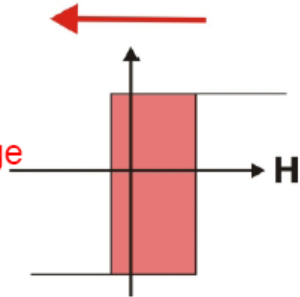
FM



FM + AFM

Exchange bias

Preferred direction of M



● Exchange bias

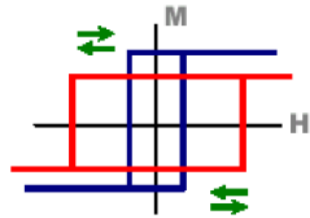
Neel (1964)

AFM (pinning layer): FeMn, MnIr, PtMn, etc.

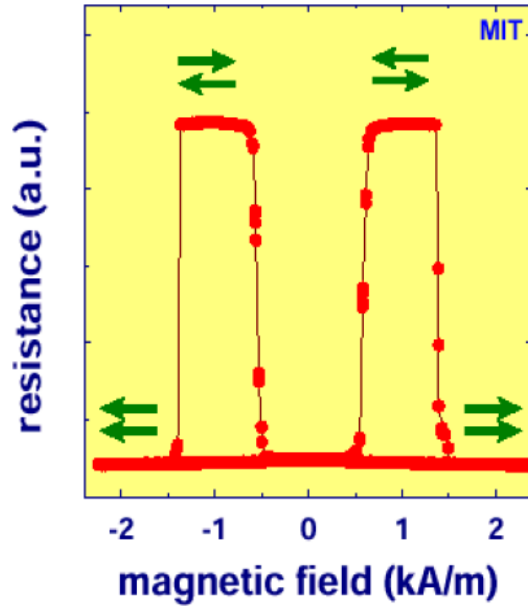
Two types of MTJ

(Magnetic Tunnel Junction)

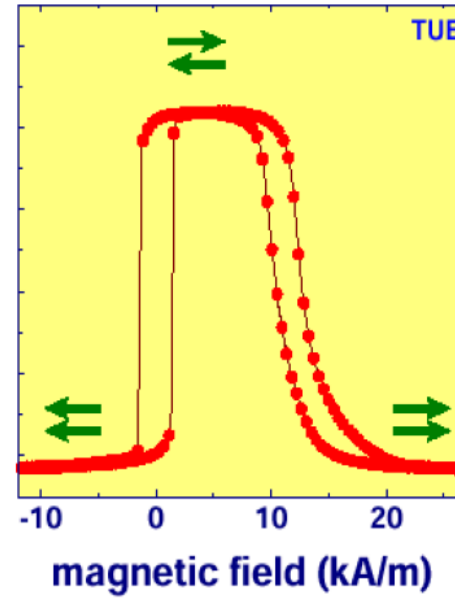
Different coercivities



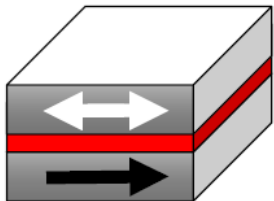
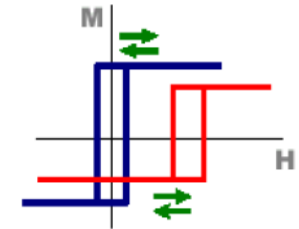
Co / Al₂O₃ / NiFe



FeMn / Co / Al₂O₃ / Co



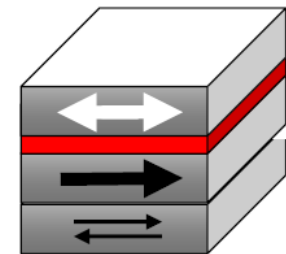
Exchange biasing using antiferromagnet



NiFe: Free layer
Al₂O₃: Tunnel barrier
Co: Pinned layer

TMR ~ 80%

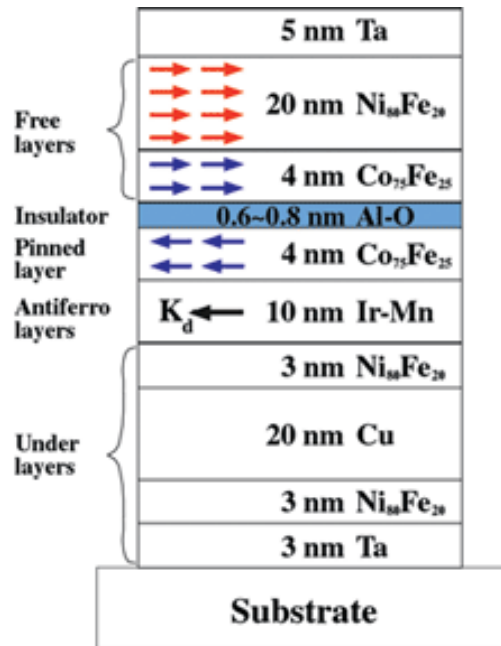
Co: Free layer
Al₂O₃: Tunnel barrier
Co: Pinned layer
FeMn: Pinning layer



S. Yuassa et al.

http://www.jst.go.jp/sicp/ws2009_sp1st/presentation/15.pdf

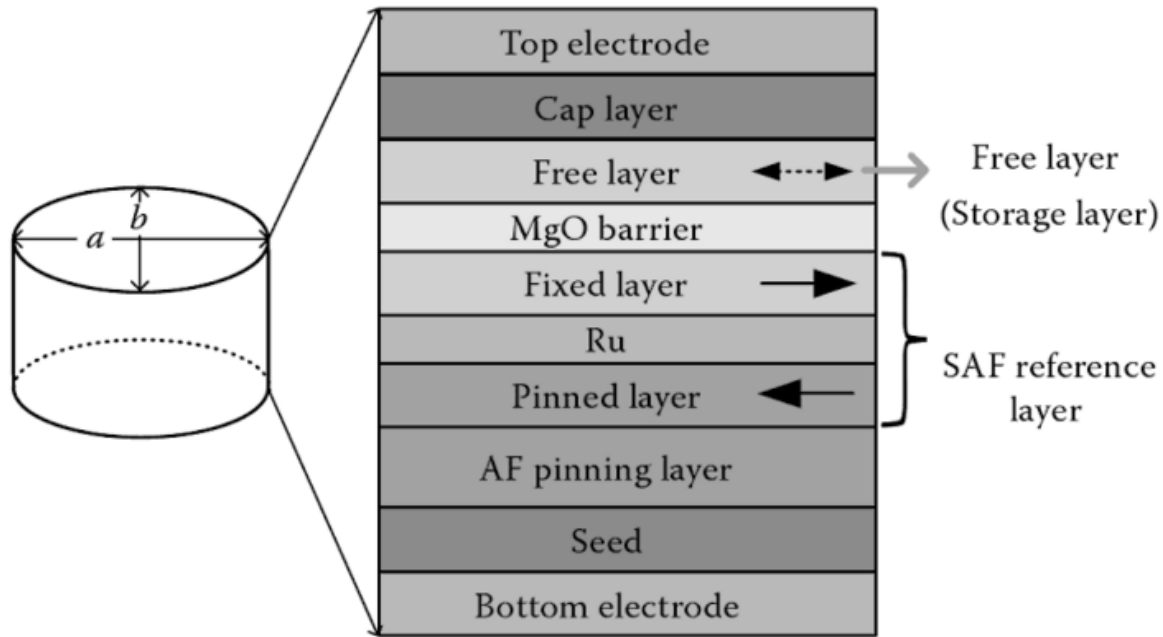
Film deposition scheme



Underlayers: to make a flat interface
induce crystalline oriented structure

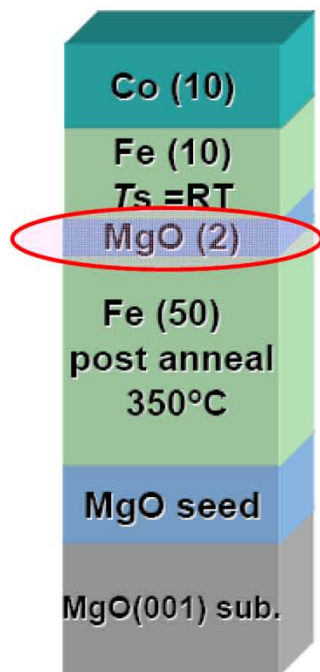
Antiferro layers : to pin the hard layer
FeMn, IrMn, NiO..

illustration of a typical MTJ structure



Structures of TMR MTJs

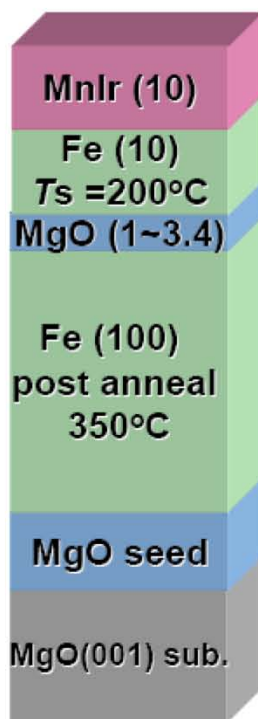
TMR ratio
= 88% @ RT



MBE

AIST

180%

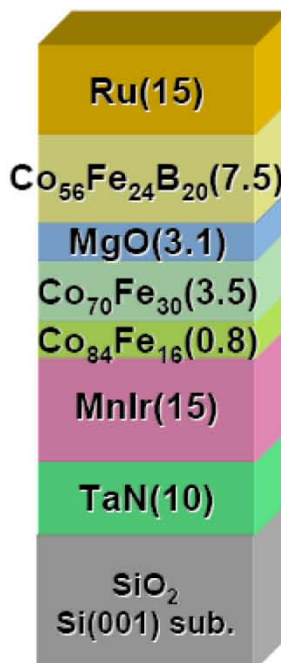


MBE

220%

(18kΩμm²)

$T_a = 350^\circ C$



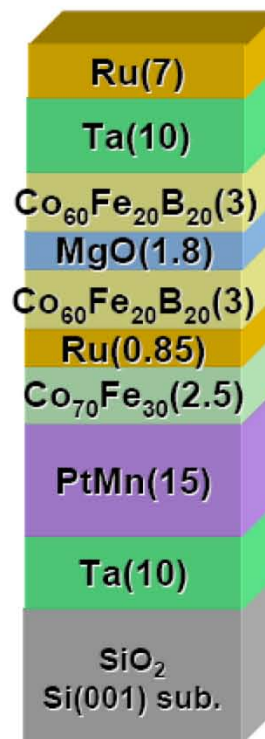
ion-beam sputtering +
MgO :reactive magnetron
sputtering

IBM

230%

(420Ωμm²)

$T_a = 360^\circ C$



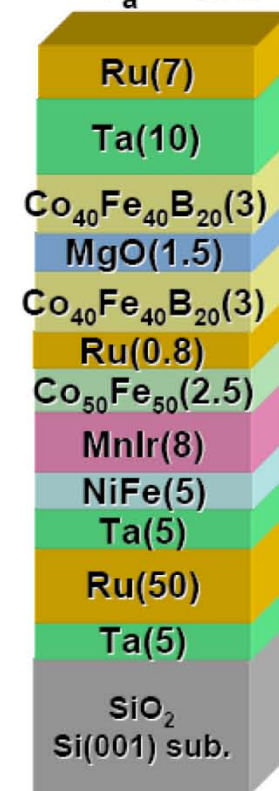
magnetron sputtering

Canon
ANELVA

> 355%

(540Ωμm²)

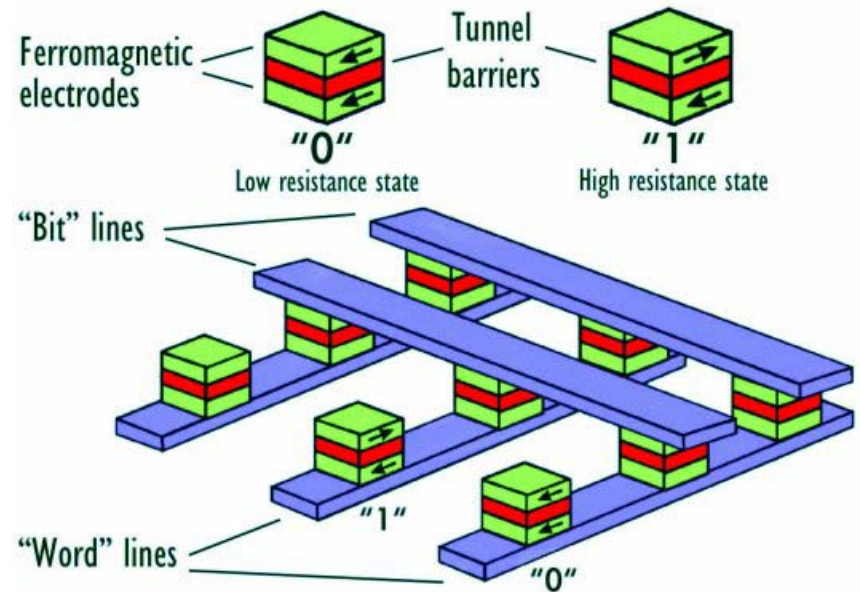
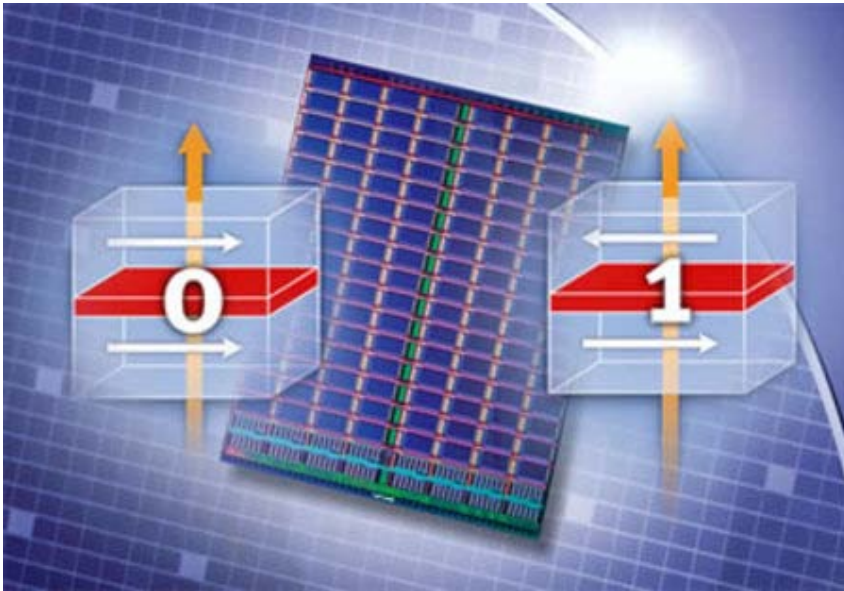
$T_a = 400^\circ C$



magnetron sputtering

Tohoku Univ.
& Hitachi

MRAM



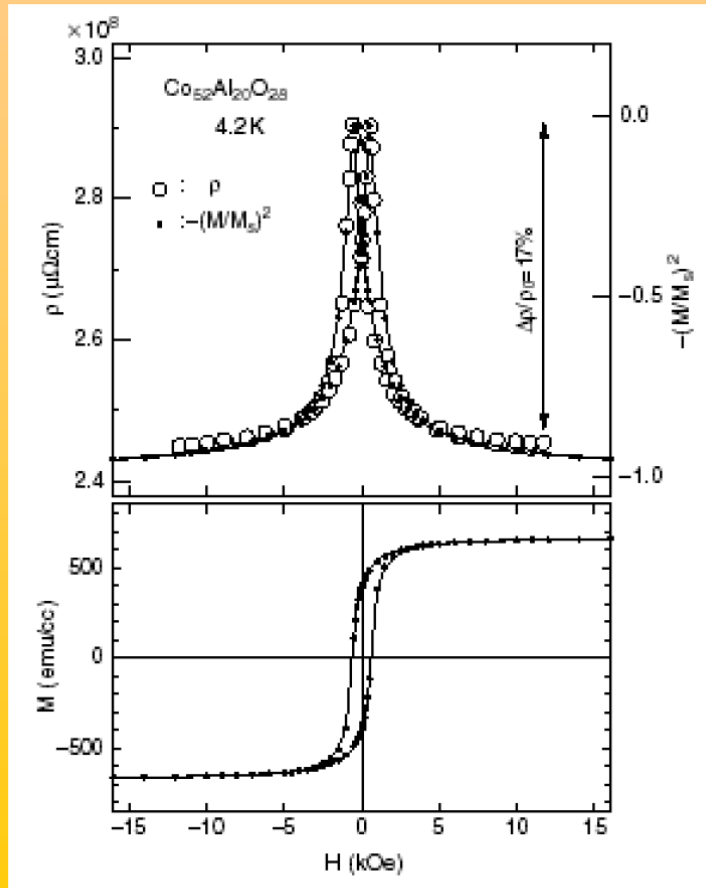
One of the two plates is a permanent magnet set to a particular polarity, the other's field will change to match that of an external field.

<https://www.westfloridacomponents.com>

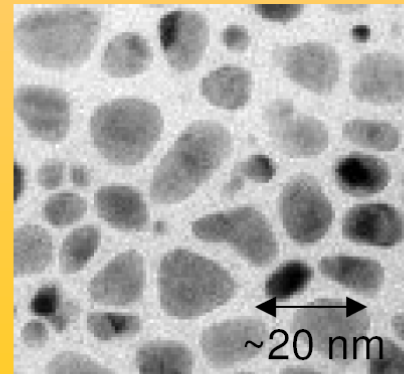
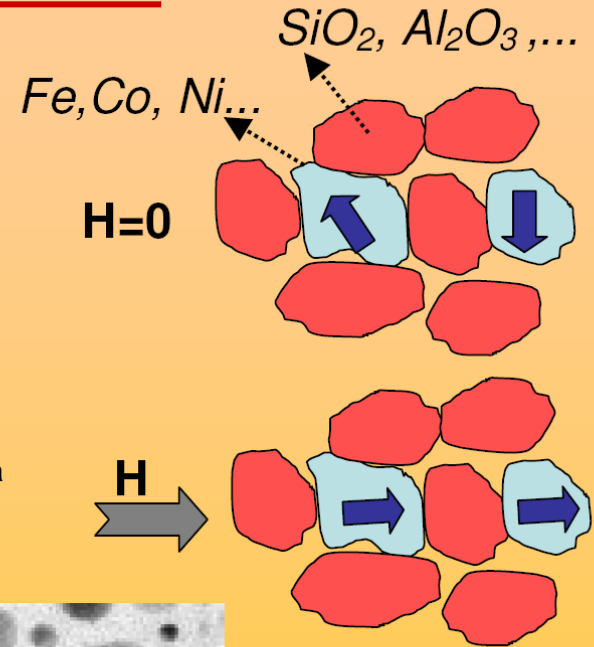
Magneto resistive random access technology (MRAM) for better memory storage

TUNNEL MR (TMR) IN GRANULAR MATERIALS

-The TMR effect can be realized in granular materials / thin films with immiscible magnetic metals / insulators due to the same physical phenomena.



J.M. de Teresa,
 Universidad de Zaragoza,
 Spain, ESM
 2005 Constanta



Gittleman et al., Phys. Rev. 5 (1972) 3609; Helman and Abeles, Phys. Rev. Lett. 37 (1976) 1429; Inoue and Maekawa, Phys. Rev. B 53 (1996) R11927; Mitani et al., J. Magn. Mater. 165 (1997) 141; Batlle and Labarta, J. Phys. D: Appl. Phys. 35 (2002) R15